

**OCTAL DAC WITH DIFFERENTIAL OUTPUTS
AND 2-BIT PER CHANNEL CMOS OUTPUT
PATTERN GENERATORS FOR ULTRASOUND TRANSMITTER**

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Rev.1.2_00

The ABLIC S-US55D2 is an octal, 12-bit, 200MSPS, Digital-to-Analog Converter (DAC) with analog differential outputs and 2-bit per channel CMOS output pattern generators. It is designed for an ultrasound linear amplifier with 3-level pulser (3LP). Each channel has a 12bit x 4096 DAC pattern memory and a 128Byte 3LP pattern memory. The S-US55D2 is suitable as the input signal pattern generator to the S-UM55L2 ultrasound transmitter.

■ Function

- Octal DAC with differential outputs and 2-bit per channel CMOS output pattern generators for an ultrasound transmitter

■ Features

<DAC>

- On-chip 12bit x4096 pattern Memory for each DAC
- 0.16 μ s to 40.96 μ s programmable delay time with 5ns resolution from TRIG signal
- 200MSPS sampling rate
- Both current output mode and voltage output mode are available.
- 14 Ω /2 Ω output impedance are selectable at voltage output mode.
- 1.28mA ~ 10.24mA selectable full-scale current @Current output mode
- 0.074V~0.592V (0.083V~0.664V) selectable full-scale voltage @voltage output mode

<3LP pattern generator>

- On-chip 128Byte pattern Memory for each 3LP pattern generator
- 0.16 μ s to 40.96 μ s programmable delay time with 5ns resolution from TRIG signal

<Others>

- Serial Peripheral Interface (SPI) for access to Memory and Register.
- 1.8V to 3.3V CMOS control logic interface
- Latch-up free, low crosstalk by SOI CMOS technology
- 68-lead 10x10mm QFN package (RoHS compliant)

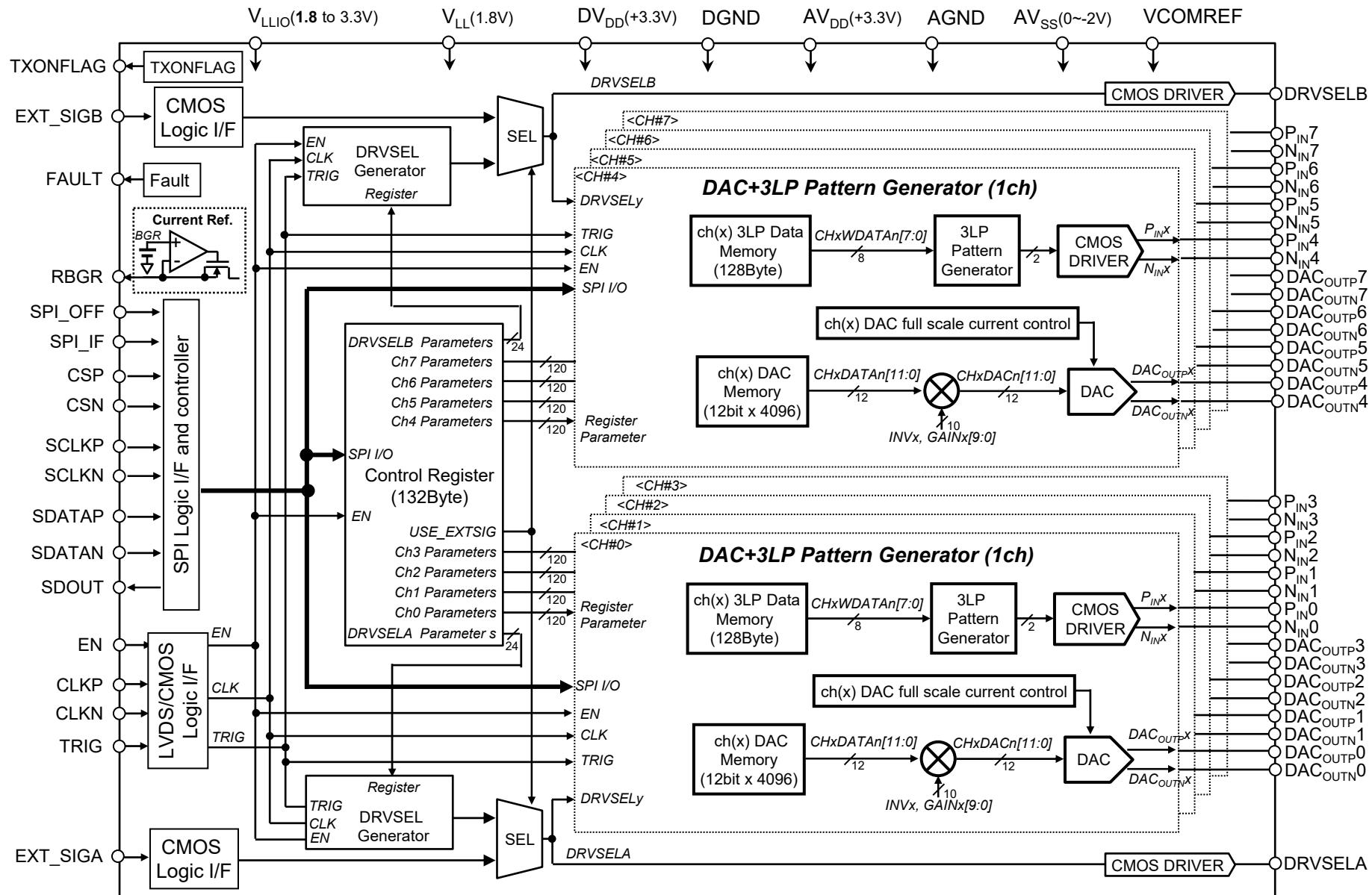
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■ Block Diagram



■ Absolute Maximum Ratings

T_a=25°C unless otherwise noted.

No.	Items	Symbol	Value	Units	Condition
1	Logic I/F voltage	V _{LLIO}	-0.4 to +4	V	
2	Logic supply voltage	V _{LL}	-0.4 to +2.3	V	
3	Positive supply voltage for DAC	AV _{DD}	-0.4 to +7	V	
4	Negative supply voltage for DAC	AV _{SS}	-7 to +0.4	V	
5	Positive to Negative voltage rail	AV _{DD} - AV _{SS}	-0.4 to +7	V	
6	LVDS Positive supply voltage	DV _{DD}	-0.4 to +7	V	
7	DAC outputs (x=0~7)	I _{DACPX} , I _{DACNX}	-0.4 to +7	V	
8	RBGR output voltage	RBGR	-0.4 to +7	V	
9	VCOMREF input voltage	VCOMREF	AV _{SS} to AV _{DD}	V	
10	Logic output voltage (x=0~7)	P _{INX} , N _{INX} , DRVSELA, DRVSELB, SDOUT, FAULT	-0.4 to +7	V	
11	Logic input voltages	CLKP, CLKN, TRIG, SPI_OFF, EN, EXT_SIGA, EXT_SIGB, CSP, CSN, SCLKP, SCLKN, SDATAP, SDATAN	-0.4 to +7	V	
12	Operating junction temperature	T _{Jop}	-20 to +125	°C	
13	Storage temperature	T _{STG}	-55 to +150	°C	
14	Maximum power dissipation	P _{Dmax}	4	W	

NOTE: Stresses beyond the absolute maximum ratings may cause permanent damage to the product.

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■ Operating Supply Voltage and Temperature

No	Items	Symbol	Min	Typ	Max	Units	Condition
1	Logic I/F voltage	V_{LLIO}	1.71	1.8 to 3.3	3.6	V	
2	Logic supply voltage ※1	V_{LL}	1.71	1.8	1.89	V	
3	LVDS Positive supply voltage	DV_{DD}	3.0	3.3	3.6	V	
4	DAC Positive supply voltage	AV_{DD}	3.0	3.3	3.6	V	
5	DAC Negative supply voltage	AV_{SS}	-2		0	V	
6	GND for LOGIC	DGND	-	0	-	V	
7	GND for DAC	AGND	-	0	-	V	
8	IC substrate voltage *	V_{SUB}	-	0	-	V	
9	DAC common voltage reference (Voltage output mode only)	VCOMREF	$AV_{SS} +1.1$		$AV_{DD} -2$	V	Register parameter OUTIFSEL[1:0]=10
			$AV_{SS} +1.2$		$AV_{DD} -2$	V	Register parameter OUTIFSEL[1:0]=11
10	Operating free-air Temperature	T_a	0		75	°C	

NOTE: * The package exposed pad internally connected to the chip substrate must be soldered to the ground.

※1. Be sure to power on VLL last

■ LVDS Differential Logic Inputs

CLKP/CLKN, CSP/CSN, SCLKP/SCLKN, SDATAP/SDATAN

No	Items	Symbol	Min	Typ	Max	Units	Condition
1	High-level input voltage	V_{IH}	1.265	-	-	V	$V_{IHCMR}(Typ)+V_{DIFF}(Min)/2$
2	Low-level input voltage	V_{IL}	-	-	1.135	V	$V_{IHCMR}(Typ)-V_{DIFF}(Min)/2$
3	Differential input voltage range	$V_{DIFF(rage)}$	0.13	0.35	0.49	$\pm V$	Same as voltage swing
4	Differential input voltage peak to peak swing	$V_{DIFF(p-p)}$	0.26	0.7	0.98	V_{pp}	Differential peak-to-peak absolute voltage swing
5	Input common mode voltage	V_{IHCMR}	0.84	1.2	1.56	V	
6	High-level input current	I_{IH}	-	-	5.8	mA	
7	Low-level input current	I_{IL}	-	-	5.8	mA	
8	Input rise/fall time	t_r, t_f	-	-	600	ps	20% to 80% of V_{DIFF}
9	Input clock frequency (Tx)	f_{CLK}	-	-	200	MHz	$CLKP/CLKN T_{CLK}=1/f_{CLK}$
	Input clock frequency (SPI)	f_{SCLK}	-	-	100	MHz	SCLKP/SCLKN (Write mode), $T_{SCLK}=1/f_{SCLK}$
			-	-	50	MHz	SCLKP/SCLKN (Read mode)
10	Clock duty cycle	D_{CLK}, D_{SCLK}	45	50	55	%	
11	SDATA setup time	t_{SU_SDATA}	2.5			ns	SDATA to SCLK rise
12	SDATA hold time	t_{HLD_SDATA}	2.5			ns	SDATA to SCLK rise
13	CS setup time	t_{SU_cs}	2.5			ns	CS to SCLK rise
14	CS hold time	t_{HLD_cs}	2.5			ns	CS to SCLK rise
15	CS width	t_{W_cs}	$1042T_{SCLK}$			ns	Write to 3LP Memory (128byte)
			$49170T_{SCLK}$			ns	Write to DAC Memory (6144Byte)
			$1074T_{SCLK}$			ns	Write to All Control Register (132Byte)
			$114T_{SCLK}$			ns	Write to common Register (12Byte)
			$138T_{SCLK}$			ns	Write to ch(x) Register (15Byte), x=0~7
			$1042T_{SCLK}$			ns	Read from 3LP Memory (128byte)
			$49170T_{SCLK}$			ns	Read from DAC Memory (6144Byte)
			$1074T_{SCLK}$			ns	Read from All control Register (132Byte)
			$34T_{SCLK}$			ns	Read CRC & Calculated CRC data (2Byte)
			$66T_{SCLK}$			ns	Read from Error Register (6Byte)

NOTE: External termination resistor (100Ω) is necessary for LVDS I/F differential inputs.

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■ CMOS Logic Inputs & Outputs

EN, TRIG, SPI_OFF, EXT_SIGA, EXT_SIGB, SDOUT, DRVSELA, DRVSELB, PINx/NINx (x=0~7),
CSP/CSN ^{*2}, SCLKP/SCLKN ^{*2}, SDATAP/SDATAN ^{*2}

No	Items	Symbol	Min	Typ	Max	Units	Condition
1	High-level logic input voltage	V_{IH}	$0.8V_{LLIO}$	-	V_{LLIO}	V	
2	Low-level logic input voltage	V_{IL}	0	-	$0.2V_{LLIO}$	V	
3	Logic input capacitance	C_{IN}	-	3	-	pF	
4	Logic input high current	I_{IH}	-10	-	10	μA	
5	Logic input low current ^{*1}	I_{IL}	-10	-	10	μA	
6	Input rise/fall time	t_r, t_f	-	-	2.0	ns	10~90% of signal
7	TRIG fall to clock rise setup time	$t_{SU_TRFtoCKR}$	1.4	-	-	ns	
8	TRIG fall to clock rise hold time	$t_{HLD_TRFtoCKR}$	1.4	-	-	ns	
9	TRIG width	t_w_{TRIG}	$6T_{CLK}$	-	-	ns	
10	High-level logic output voltage	V_{OH}	$0.8V_{LLIO}$	-	V_{LLIO}	V	SDOUT, PINx/NINx(x=0~7), DRVSELA, DRVSELB
11	Low-level logic output voltage	V_{OL}	0	-	$0.2V_{LLIO}$	V	
12	Logic output off leak current	$I_{OFFLEAK}$	-10	-	10	μA	SDOUT HiZ output
13	SDOUT propagation delay	t_{D_SDOUT}	10	13	17	ns	$V_{LLIO}=3.3V$
			12	15	19	ns	$V_{LLIO}=2.5V$
			14	18	23	ns	$V_{LLIO}=1.8V$

Remark:

*1) EN has 50 μA leakage at $V_{LLIO}=2.5V$ due to 50k Ω internal pull-up resistor.

*2) Single-ended CMOS interface is also available for SPI pins of CSP/N, SCLKP/N and SDATAP/N by setting SPI-IF to "Hi".

When SPI-IF is set to "Hi", SPI CMOS inputs must be connected to P-terminals of SPI pins (CSP, SCLKP and SDATAP) and N-terminals of SPI pins (CSN, SCLKN and SDATAN) are need to be open.

(As for the N-terminals of SPI pins (CSN, SCLKN and SDATAN), half of V_{LLIO} ($V_{LLIO}/2$) is biased internally.)

■ Open Drain Outputs

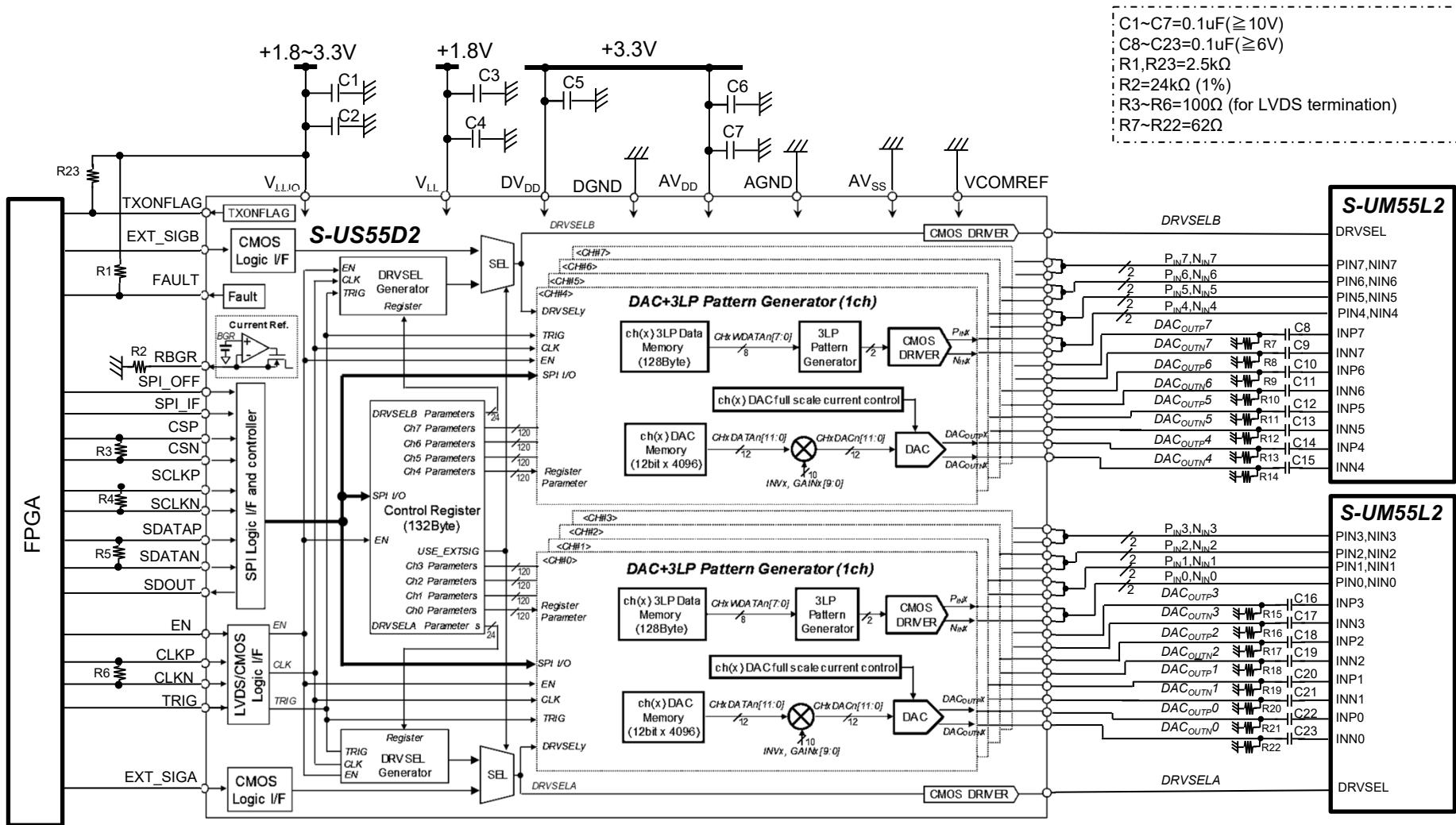
FAULT, TXONFLAG

No	Items	Symbol	Min	Typ	Max	Units	Condition
1	Pull-up voltage	$V_{PUFAULT}$	-	-	V_{LLIO}	V	Connected to V_{LLIO} with external pull-up resistor (R1, shown in page 9)
2	Output low voltage	$V_{OLFAULT}$	-	-	0.5	V	Open drain MOS is Active. $V_{LLIO}=2.5V$
3	Output current	I_{FAULT}	-	1.0	-	mA	External pull-up resistor (R1) = $2.5k\Omega$
4	Off leakage current	$I_{OFFLEAK}$	-10	-	10	μA	Open drain MOS is disabled. (HiZ)

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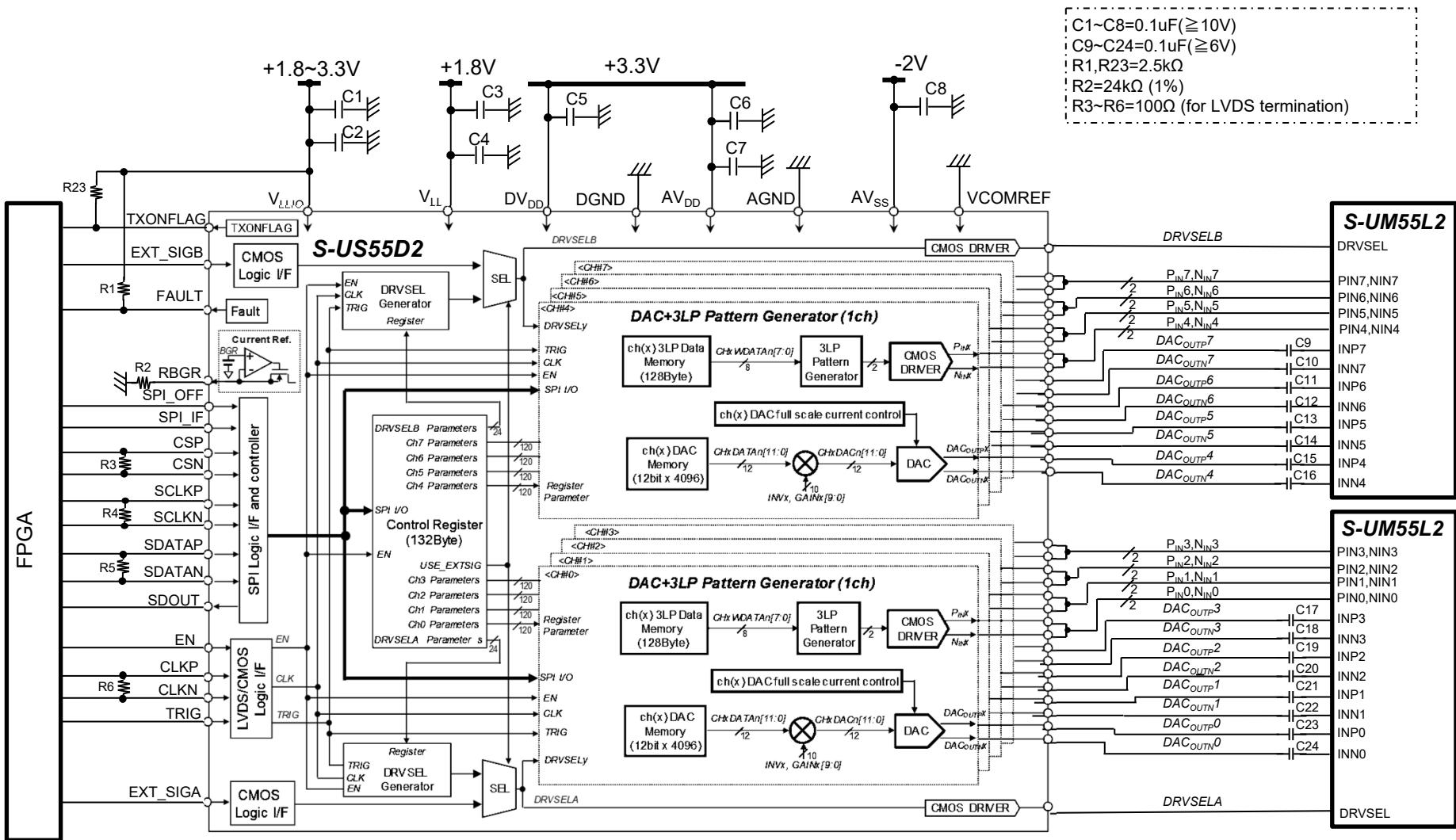
■ Typical Application Circuit (current output)



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■ Typical Application Circuit (voltage output)



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■ Operating Supply Currents (1)

$V_{LLIO}=2.5V$, $V_{LL}=1.8V$, $DV_{DD}=AV_{DD}=3.3V$, $AV_{SS}=-2V$, $T_A=25^\circ C$, $CLKP/CLKN=200MHz$,
PINx/NINx(x=0~7) load = 10pF, unless otherwise specified.

No	Items		Symbol	Min	Typ	Max	Units	Condition
1	V_{LLIO} current		I_{LLIOQD}	-	0.06	-	mA	
2	V_{LL} current		I_{LLQD}	-	0.11	-	mA	
3	DV_{DD} current	SPI_OFF="1",SPI_IF="0/1"	I_{DDDQD}	-	0.7	-	mA	Quiescent current-1
		SPI_OFF="0",SPI_IF="1"		-	1.3	-	mA	Quiescent current at chip is disabled. EN="1"(Disable) CLKP/CLKN is stopped.
		SPI_OFF="0",SPI_IF="0"		-	6.3	-	mA	
4	AV_{DD} current		I_{ADDQD}	-	2.8	-	mA	
5	AV_{SS} current		I_{ASSQD}	-	0.65	-	mA	
6	V_{LLIO} current		$I_{LLIOQE1}$	-	0.1	-	mA	Quiescent current-2
7	V_{LL} current		I_{LLQE1}	-	22.3	-	mA	Quiescent current at chip is enable and all DAC is bias-off, Both DAC and 3LP-PG are not operated. EN="0"(Enable) CLKP/CLKN is activated (200MHz) DACTXCHx="0" (x=0~7) TLPTXCHx="0" (x=0~7) PWRSAVE="1"
8	DV_{DD} current	SPI_OFF="1",SPI_IF="0/1"	I_{DDDQE1}	-	3.2	-	mA	
		SPI_OFF="0",SPI_IF="1"		-	3.8	-	mA	
		SPI_OFF="0",SPI_IF="0"		-	8.6	-	mA	
9	AV_{DD} current		I_{ADDQE1}	-	2.9	-	mA	
10	AV_{SS} current		I_{ASSQE1}	-	0.65	-	mA	
11	V_{LLIO} current		$I_{LLIOQE2}$	-	0.1	-	mA	
12	V_{LL} current		I_{LLQE2}	-	22.3	-	mA	Quiescent current-3
13	DV_{DD} current	SPI_OFF="1",SPI_IF="0/1"	I_{DDDQE2}	-	3.2	-	mA	Quiescent current at chip is enable and all DAC is bias-on, Both DAC and 3LP-PG are not operated. EN="0"(Enable) CLKP/CLKN is activated (200MHz)
		SPI_OFF="0",SPI_IF="1"		-	3.8	-	mA	
		SPI_OFF="0",SPI_IF="0"		-	8.6	-	mA	
14	AV_{DD} current	ICSELx[2:0] = "111"	I_{ADDQE2}	-	88	-	mA	DACTXCHx="0" (x=0~7) TLPTXCHx="0" (x=0~7) PWRSAVE="0"
		ICSELx[2:0] = "000"		-	14	-	mA	
15	AV_{SS} current		I_{ASSQE2}	-	0.65	-	mA	

■ Operating Supply Currents (2)

$V_{LLIO}=2.5V$, $V_{LL}=1.8V$, $DV_{DD}=AV_{DD}=3.3V$, $AV_{SS}=-2V$, $T_A=25^\circ C$, $CLKP/CLKN=200MHz$, unless otherwise specified.

No	Items	Symbol	Min	Typ	Max	Units	Condition
16	V_{LLIO} current	$I_{LLIODAC1}$	-	0.1	-	mA	DAC operating current -1
17	V_{LL} current	I_{LLDAC1}	-	229	-	mA	Operating current with current DAC. EN="0"(Enable)
18	DV_{DD} current	$I_{DDDDAC1}$	-	3.2	-	mA	DRVSELA/B ="1" (DAC is selected)
			-	3.8	-	mA	DAC output load = $50\Omega//2pF$
			-	8.6	-	mA	All channel active
19	AV_{DD} current	$I_{ADDDAC1}$	-	229	-	mA	CW 5MHz sin wave outputs
			-	156	-	mA	OUTIFSEL[1:0] ="00" (Current output mode) DACTXCHx="1" (x=0~7)
20	AV_{SS} current	$I_{ASSDAC1}$	-	0.65	-	mA	
21	V_{LLIO} current	$I_{LLIODAC2}$	-	0.1	-	mA	
22	V_{LL} current	I_{LLDAC2}	-	229	-	mA	DAC operating current -2
23	DV_{DD} current	$I_{DDDDAC2}$	-	3.2	-	mA	Operating current with voltage DAC ($Ro=14\Omega$). EN="0"(Enable)
			-	3.8	-	mA	DRVSELA/B ="1" (DAC is selected)
			-	8.6	-	mA	DAC output load = $500\Omega//2pF$
24	AV_{DD} current	$I_{ADDDAC2}$	-	206	-	mA	All channel active
			-	183	-	mA	CW 5MHz sin wave outputs
25	AV_{SS} current	$I_{ASSDAC2}$	-	62	-	mA	OUTIFSEL[1:0] ="10" (Voltage mode $Ro=14\Omega$)
			-	40	-	mA	DACTXCHx="1" (x=0~7)
26	V_{LLIO} current	$I_{LLIODAC3}$	-	0.1	-	mA	
27	V_{LL} current	I_{LLDAC3}	-	229	-	mA	DAC operating current -3
28	DV_{DD} current	$I_{DDDDAC3}$	-	3.2	-	mA	Operating current with voltage DAC ($Ro=2\Omega$). EN="0"(Enable)
			-	3.8	-	mA	DRVSELA/B ="1" (DAC is selected)
			-	8.6	-	mA	DAC output load = $500\Omega//2pF$
29	AV_{DD} current	$I_{ADDDAC3}$	-	310	-	mA	All channel active
			-	287	-	mA	CW 5MHz sin wave outputs
30	AV_{SS} current	$I_{ASSDAC3}$	-	163	-	mA	OUTIFSEL[1:0] ="11" (Voltage mode $Ro=2\Omega$)
			-	140	-	mA	DACTXCHx="1" (x=0~7)

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■ Operating Supply Currents (3)

$V_{LLIO}=2.5V$, $V_{LL}=1.8V$, $DV_{DD}=AV_{DD}=3.3V$, $AV_{SS}=-2V$, $T_A=25^\circ C$, $CLKP/CLKN=200MHz$, $PINx/NINx(x=0\sim7)$ load = $10pF$, unless otherwise specified.

No	Items		Symbol	Min	Typ	Max	Units	Condition
1	V_{LLIO} current		$I_{LLIO3LP1}$	-	4.0	-	mA	3LP Pattern Generator operating current-1
2	V_{LL} current		I_{LL3LP1}	-	24	-	mA	Operating current with 3LP Pattern Generator at DAC is bias-off, EN="0"(Enable)
3	DV_{DD} current	SPI_OFF="1",SPI_IF="0/1"	$I_{DDD3LP1}$	-	3.2	-	mA	DRVSELA/B ="0" (3LP DATA is selected)
		SPI_OFF="0",SPI_IF="1"		-	3.8	-	mA	All channel active, CW 5MHz BIP wave outputs
		SPI_OFF="0",SPI_IF="0"		-	8.6	-	mA	DACTXCHx="0" ($x=0\sim7$) TLPTXCHx="1" ($x=0\sim7$) PWRSAVE="1"
4	AV_{DD} current		$I_{ADD3LP1}$	-	3.0	-	mA	
5	AV_{SS} current		$I_{ASS3LP1}$	-	0.65	-	mA	
6	V_{LLIO} current		$I_{LLIO3LP2}$	-	4.0	-	mA	3LP Pattern Generator operating current-2
7	V_{LL} current		I_{LL3LP2}	-	24	-	mA	Operating current with 3LP Pattern Generator at current DAC is bias-on, EN="0"(Enable)
8	DV_{DD} current	SPI_OFF="1",SPI_IF="0/1"	$I_{DDD3LP2}$	-	3.2	-	mA	DRVSELA/B ="0" (3LP DATA is selected)
		SPI_OFF="0",SPI_IF="1"		-	3.8	-	mA	All channel active, CW 5MHz BIP wave outputs
		SPI_OFF="0",SPI_IF="0"		-	8.6	-	mA	OUTIFSEL[1:0] ="00" (Current output mode) DACTXCHx="0/1" ($x=0\sim7$) TLPTXCHx="1" ($x=0\sim7$) PWRSAVE="0"
9	AV_{DD} current	ICSELx[2:0] ="111"	$I_{ADD3LP2}$	-	88	-	mA	
10		ICSELx[2:0] ="000"		-	14	-	mA	
11	AV_{SS} current		$I_{ASS3LP2}$	-	0.65	-	mA	
12	V_{LLIO} current		$I_{LLIO3LP3}$	-	4.0	-	mA	3LP Pattern Generator operating current-3
13	DV_{DD} current	SPI_OFF="1",SPI_IF="0/1"	$I_{DDD3LP3}$	-	3.2	-	mA	Operating current with 3LP Pattern Generator at voltage DAC is bias-on, EN="0"(Enable)
SPI_OFF="0",SPI_IF="1"		-		3.8	-	mA	DRVSELA/B ="0" (3LP DATA is selected)	
SPI_OFF="0",SPI_IF="0"		-		8.6	-	mA	All channel active, CW 5MHz BIP wave outputs	
14	AV_{DD} current	ICSELx[2:0] ="111"	$I_{ADD3LP3}$	-	64	-	mA	OUTIFSEL[1:0] ="10" (Voltage output mode $R_o=14\Omega$)
		ICSELx[2:0] ="000"		-	41	-	mA	DACTXCHx="0/1" ($x=0\sim7$) TLPTXCHx="1" ($x=0\sim7$) PWRSAVE="0"
15	AV_{SS} current	ICSELx[2:0] ="111"	$I_{ASS3LP3}$	-	62	-	mA	
		ICSELx[2:0] ="000"		-	40	-	mA	

■ Static Characteristics

$V_{LLIO}=2.5V$, $V_{LL}=2.5V$, $DV_{DD}=AV_{DD}=3.3V$, $T_A=25^\circ C$, $CLKP/CLKN=200MHz$, unless otherwise specified.

No	Items	Symbol	Min	Typ	Max	Unit	Note
1	DAC Resolution			12		bits	
2	DAC Differential Nonlinearity	DNL _X	-2	+/-1	2	LSB	Differential Non-linearity of DAC differential outputs
3	DAC Integral Nonlinearity	INL _X	-3.5	+/-1	3.5	LSB	Integral Non-linearity of DAC differential outputs
4	DAC Full-scale output current (Current output mode)	I _{FSX}	1.28		10.24	mA	Register OUTIFSEL[1:0] = "00"
5	DAC Full-scale output voltage (Voltage output mode)	V _{FSX}	0.077		0.592	V	No load, Register OUTIFSEL[1:0] = "10" ($R_o=14\Omega$)
			0.083		0.664		No load, Register OUTIFSEL[1:0] = "11" ($R_o=2\Omega$)
6	DAC digital gain	G _{DX}	-1		1	V/V	programable with register GAINX[9:0] and INV _X , except for 0, step=1/1024
7	DAC differential current offset error (Current output mode)	I _{OFSX}	-0.8		+0.8	LSB	Without adjustment
			+/-0.375			LSB	Adjusted with Register OFSADJ _X [6:0]
8	DAC differential voltage offset error (Voltage output mode)	V _{OFSX}	-5		+5	LSB	Without adjustment, ICSEL[2:0] = "111" (V_{FSX} is max)
			+/-0.375			LSB	Adjusted with Register OFSADJ _X [6:0], ICSEL[2:0] = "111"
9	DAC Gain error	G _{ERRORX}	-4	+/-1	+4	%	Without adjustment
			+/-0.06				Adjusted with Register GAINADJ _X [6:0]
10	DAC ch to ch Gain matching	ΔG_{CH-CH}	+0.6	+/-0.1	-0.6	%	Without adjustment
11	DAC output impedance (Voltage output mode only)	R _O	100M			Ω	DAC is disabled
			18				DAC is active, OUTIFSEL[1:0] = "10"
			3.5				DAC is active, OUTIFSEL[1:0] = "11"
12	DAC output common voltage error	V _{OFS_COM}	-10		10	mV	Voltage output only (OUTIFSEL[1:0] = "10" or "11")
13	Internal BGR reference voltage	V _{BGR}		1.207		V	

OCTAL DAC WITH DIFFERENTIAL OUTPUTS AND 2-BIT PER CHANNEL CMOS OUTPUT PATTERN GENERATORS FOR ULTRASOUND TRANSMITTER

Rev.1.2_00

S-US55D2

■ Dynamic Characteristics

$V_{LLIO}=2.5V$, $V_{LL}=1.8V$, $DV_{DD}=AV_{DD}=3.3V$, $V_{SS}=-2V$, $T_A=25^\circ C$, $CLKP/CLKN=200MHz$, $ICSELx[2:0]=111$, $VCOMREF=0V$, unless otherwise specified.

No.	Items	Symbol	Min	Typ	Max	Unit	Note
1	DAC Spurious Free Dynamic Range	SFDR	49	55		dBc	$f_{CLK}=200MHz$, $ICSELx[2:0]=111$, Current output, 5MHz
2	DAC output noise (load noise is included, @5MHz)	No		2		nv/rtHz	Current output (OUTIFSEL[1:0] = "00"), load=50Ω//2pF
				4.5			Voltage output (OUTIFSEL[1:0] = "10"), load=500Ω//2pF
				6			Voltage output (OUTIFSEL[1:0] = "11"), load=500Ω//2pF
3	DAC differential output voltage	DR_{VOUT}		1.03		Vpp	Current output (OUTIFSEL[1:0] = "00") load=50Ω//2pF
				1.15			Voltage output (OUTIFSEL[1:0] = "10") load=500Ω//2pF
				1.33			Voltage output (OUTIFSEL[1:0] = "11") load=500Ω//2pF
4	DAC output propagation delay (From programmed delay clock rise)	t_{PD_DAC}		14		ns	Current output (OUTIFSEL[1:0] = "00") load=50Ω//2pF
				16			Voltage output (OUTIFSEL[1:0] = "10") load=500Ω//2pF
				17.5			Voltage output (OUTIFSEL[1:0] = "11") load=500Ω//2pF
5	DAC output rise/fall time (full-scale swing, 10%-90%)	t_{RF_DAC}		3		ns	Current output (OUTIFSEL[1:0] = "00") load=50Ω//2pF
				8			Voltage output (OUTIFSEL[1:0] = "10") load=500Ω//2pF
				5.5			Voltage output (OUTIFSEL[1:0] = "11") load=500Ω//2pF
6	DAC output current settling time (full-scale step, settling to <+/-0.1%)	t_{SET_DAC}		9		ns	Current output (OUTIFSEL[1:0] = "00") load=50Ω//2pF
				22			Voltage output (OUTIFSEL[1:0] = "10") load=500Ω//2pF
				26			Voltage output (OUTIFSEL[1:0] = "11") load=500Ω//2pF
7	3LP Data output propagation delay	t_{PD_3LP}		11		ns	From programmed delay clock rise edge
8	3LP Data output rise/fall time	t_{RF_3LP}		1	2	ns	load = 10pF
9	DRVSEL output propagation delay	t_{PD_DRVSEL}		12		ns	From programmed wait clock rise edge
10	DRVSEL output rise/fall time	t_{RF_DRVSEL}		1	2	ns	load = 10pF

■ Tx Pattern Width and Delay Digital Control Table

Clock frequency = 200MHz ($T_{CLK}=5\text{ns}$)

No	Items	Symbol	Min	Typ	Max	Unit	Note
1	DRVSELy(y=A,B) wait time from TRIG fall edge	$T_{WAIT_DRVSELy}$	0.16		40.955	μs	$T_{WAIT_DRVSELy} = T_{CLK} * (32 * WAITy + 31)$ WAITy(=0~255) is decimal number of WAITy[7:0]
2	DRVSELy(y=A,B) wait time step	ΔT_{WAIT_DRVSEL}		0.16		μs	$\Delta T_{WAIT_DRVSEL} = 32 * T_{CLK}$
3	DRVSELy(y=A,B) "high" period	$T_{WIDTH_DRVSELy}$	0			ms	If WIDTHy[15:0]= all high, Hi state is kept until next Trig rise edge or it is reset by "EN". Else, $T_{WIDTH_DRVSELy}(=0\sim10.48544\text{ms}) = 32 * T_{CLK} * WIDTHy$ WIDTHy(=0~65534) is decimal number of WIDTHy[15:0]
4	DRVSELy(y=A,B) "high" period step	ΔT_{WIDTH_DRVSEL}		0.16		μs	$\Delta T_{WIDTH_DRVSEL} = 32 * T_{CLK}$
5	DRVSELy(y=A,B) L to H settling	T_{PON_DRV}			3.2	μs	During 640 clock cycle (3.2us) from DRVSEL rise/fall edge. DAC/3LP output for Tx is not allowed.
6	DRVSELy(y=A,B) H to L settling	T_{POFF_DRV}			3.205	μs	
7	DAC clock rate	$f_{DAC-CLK}$			200	Mbps	
8	Initial wait time for DAC/3LP data output from TRIG fall edge	T_{INIT}		0.16		μs	$\Delta T_{INIT} = 32 * T_{CLK}$
9	CHx(x=0~7) delay range of DAC output from TRIG fall edge	T_{DL_CHxDAC}	0.16		41.115	μs	$T_{DL_CHxDAC} = (32 + DAC_DLx) * T_{CLK}$ DAC_DLx(=0~8191) is a decimal number of DAC_DLx [12:0]
10	CHx delay delta resolution of DAC output (x=0~7)	ΔT_{DL_CHxDAC}		5		ns	$\Delta T_{DL_CHxDAC} = T_{CLK}$
11	Ch#x(x=0~7) Tx pulse width of 3LP	$T_{CHxWIDTHn}$	10		325	ns	$T_{CHxWIDTHn} [\text{ns}] = T_{CLK} * (CHxWIDTHn + 2)$ CHxWIDTHn(=0~63) is decimal number of CHxWIDTHn[5:0] in memory #n, n=0~127
12	Tx pulse width resolution of 3LP	$\Delta T_{CHxWIDTHn}$		5		ns	$\Delta T_{CHxWIDTHn} = T_{CLK}$
13	CHx(x=0~7) delay range of 3LP Tx output from TRIG fall edge	T_{DL_CHx3LP}	0.16		41.115	μs	$T_{DL_CHx3LP} = (32 + TLP_DLx) * T_{CLK}$ TLP_DLx(=0~8191) is a decimal number of TLP_DLx [12:0]
14	CHx(x=0~7) delay delta resolution of TLP output	ΔT_{DL_CHx3LP}		5		ns	$\Delta T_{DL_CHx3LP} = T_{CLK}$

※1 . In case of USE_EXTSIG=0 , DAC_DLx=0~639(decimal number) cannot be used due to restrictions with DRVSEL.

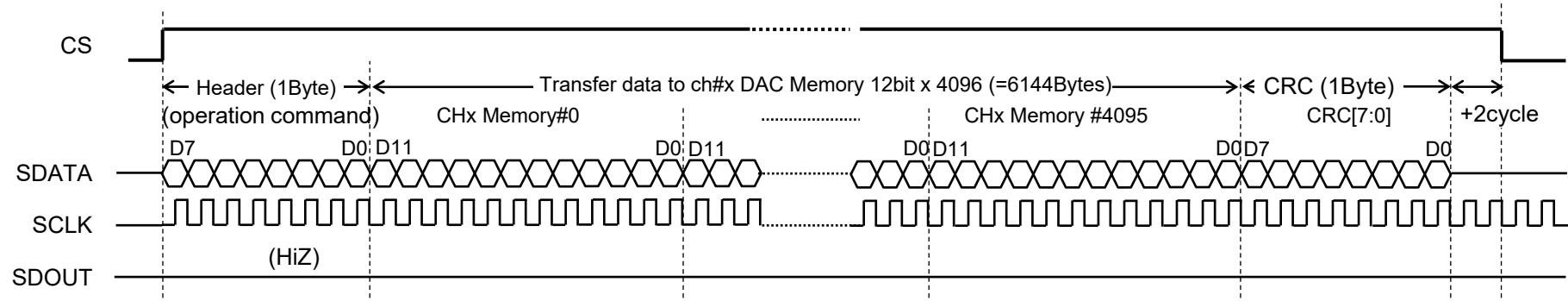
■ SPI Header Configuration

SDATA Control Header (First 1Byte of SDATA)								SPI operation
D7(MSB)	D6	D5	D4	D3	D2	D1	D0(LSB)	
0	*	*	*	*	*	*	*	Hold
1	0	0	0	1	0	0	0	Write to all-channel 3LP Memory at the same time (128Byte)
					0	0	0	Write to CH0 3LP Memory (128Byte)
					0	0	1	Write to CH1 3LP Memory (128Byte)
					0	1	0	Write to CH2 3LP Memory (128Byte)
					0	1	1	Write to CH3 3LP Memory (128Byte)
					1	0	0	Write to CH4 3LP Memory (128Byte)
					1	0	1	Write to CH5 3LP Memory (128Byte)
					1	1	0	Write to CH6 3LP Memory (128Byte)
					1	1	1	Write to CH7 3LP Memory (128Byte)
		0	1	1	0	1	0	Write to all-channel DAC Memory at the same time (6144Byte)
					0	0	0	Write to CH0 DAC Memory (6144Byte)
					0	0	1	Write to CH1 DAC Memory (6144Byte)
					0	1	0	Write to CH2 DAC Memory (6144Byte)
					0	1	1	Write to CH3 DAC Memory (6144Byte)
					1	0	0	Write to CH4 DAC Memory (6144Byte)
					1	0	1	Write to CH5 DAC Memory (6144Byte)
					1	1	0	Write to CH6 DAC Memory (6144Byte)
					1	1	1	Write to CH7 DAC Memory (6144Byte)
1	1	1	0	1	1	0	0	Write to Register 132Byte(#0~#131)
					1	0	0	Write to Register 12Byte(#0~#11)
					0	0	0	Write to Register 15Byte(#12~#26)
					0	0	1	Write to Register 15Byte(#27~#41)
					0	1	0	Write to Register 15Byte(#42~#56)
					0	1	1	Write to Register 15Byte(#57~#71)
					1	0	0	Write to Register 15Byte(#72~#86)
					1	0	1	Write to Register 15Byte(#87~#101)
					1	1	0	Write to Register 15Byte(#102~#116)
					1	1	1	Write to Register 15Byte(#117~#131)
		1	1	*	*	*	*	Don't use
1	1	0	0	1	0	0	0	Don't use
					0	0	0	Read from CH0 3LP Memory (128Byte)
					0	0	1	Read from CH1 3LP Memory (128Byte)
					0	1	0	Read from CH2 3LP Memory (128Byte)
					0	1	1	Read from CH3 3LP Memory (128Byte)
					1	0	0	Read from CH4 3LP Memory (128Byte)
					1	0	1	Read from CH5 3LP Memory (128Byte)
					1	1	0	Read from CH6 3LP Memory (128Byte)
					1	1	1	Read from CH7 3LP Memory (128Byte)
		0	1	1	0	1	0	Read from CH0 DAC Memory (6144Byte)
					0	0	1	Read from CH1 DAC Memory (6144Byte)
					0	1	0	Read from CH2 DAC Memory (6144Byte)
					0	1	1	Read from CH3 DAC Memory (6144Byte)
					1	0	0	Read from CH4 DAC Memory (6144Byte)
					1	0	1	Read from CH5 DAC Memory (6144Byte)
					1	1	0	Read from CH6 DAC Memory (6144Byte)
					1	1	1	Read from CH7 DAC Memory (6144Byte)
		1	0	0	*	*	*	Read from Register 132Byte(#0~#131)
		1	0	1	*	*	*	Don't use
		1	1	0	*	*	*	Read from CRC[7:0] & CAL_CRC[7:0] (2Byte)
		1	1	1	*	*	*	Read from ERROR[47:0] (6byte)

Note: Control Headers which don't listed in the above table are prohibited.

■ Access to DAC Memory with SPI

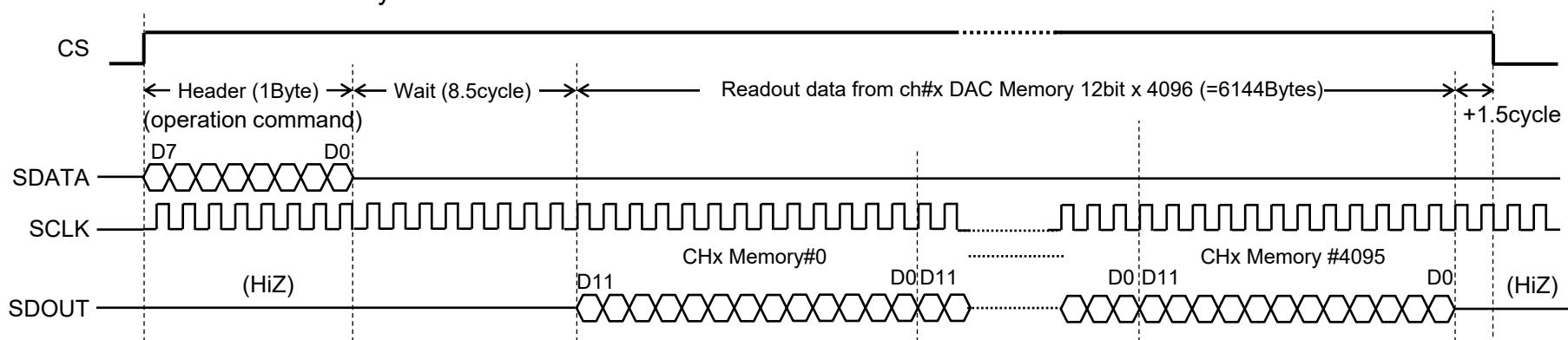
◆ Write to ch#x DAC Memory



Note:

In "WRITE" operation with SPI, internal logic circuit also calculates the CRC ,and writes it to internal Register CAL_CRC[7:0]. If CAL_CRC[7:0] unmatched transferred CRC data (CRC[7:0]), corresponding ERROR bit is set to "1" and FAULT is reported until ERROR bit is cleared.

◆ Read from ch#x DAC Memory

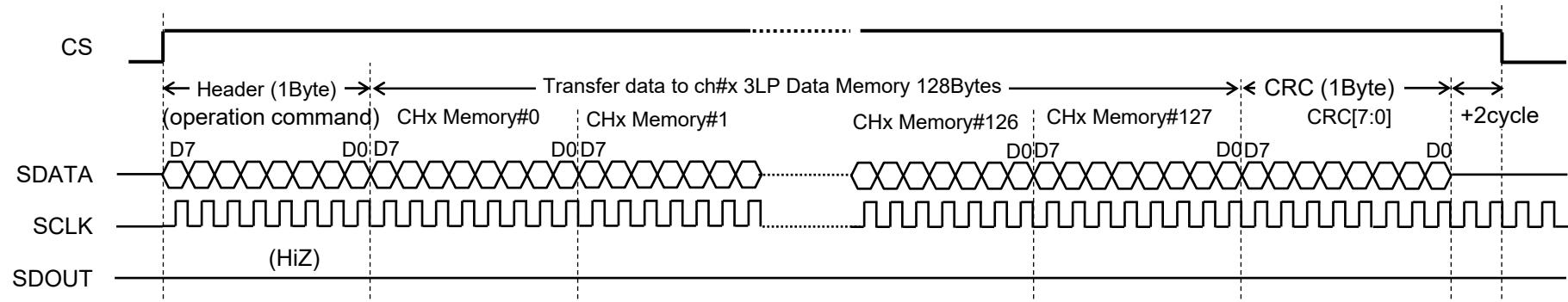


Note:

In case of "READ" operation, SDATA inputs except for Header are ignored. (CRC error detection is disabled)

■ Access to 3LP Data Memory with SPI

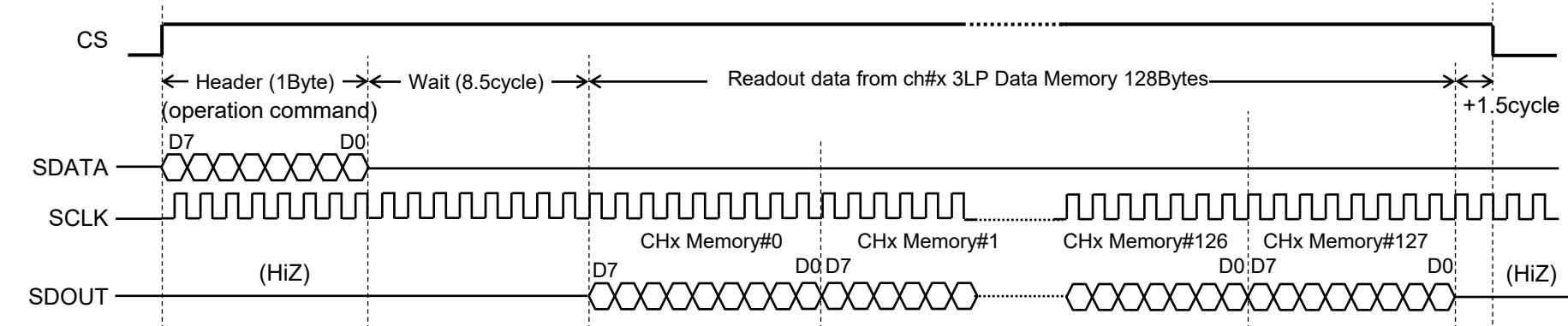
◆ Write to ch#x 3LP Data Memory



Note:

In "WRITE" operation with SPI, internal logic circuit also calculates the CRC ,and writes it to internal Register CAL_CRC[7:0]. If CAL_CRC[7:0] unmatched transferred CRC data (CRC[7:0]), corresponding ERROR bit is set to "1" and FAULT is reported until ERROR bit is cleared.

◆ Read from ch#x 3LP Data Memory

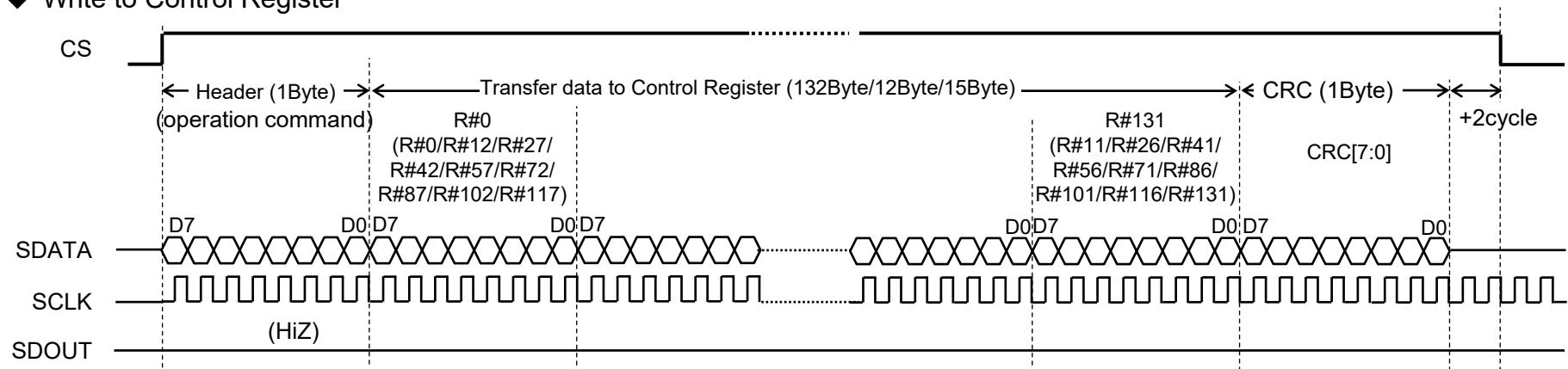


Note:

In case of "READ" operation, SDATA inputs except for Header are ignored. (CRC error detection is disabled)

■ Access to Control Register with SPI

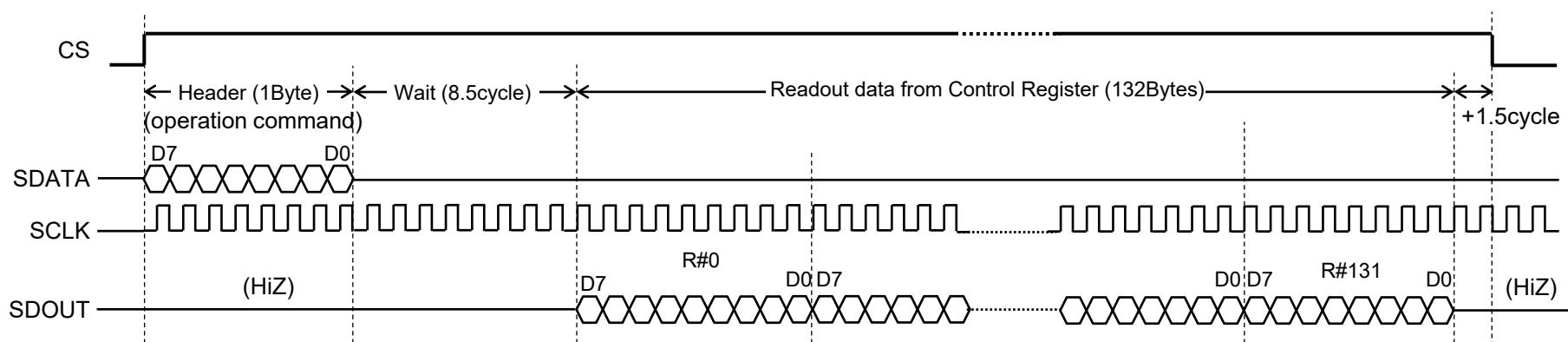
◆ Write to Control Register



Note:

In "WRITE" operation with SPI, internal logic circuit also calculates the CRC ,and writes it to internal Register CAL_CRC[7:0]. If CAL_CRC[7:0] unmatched transferred CRC data (CRC[7:0]), corresponding ERROR bit is set to "1" and FAULT is reported until ERROR bit is cleared.

◆ Read from control Register

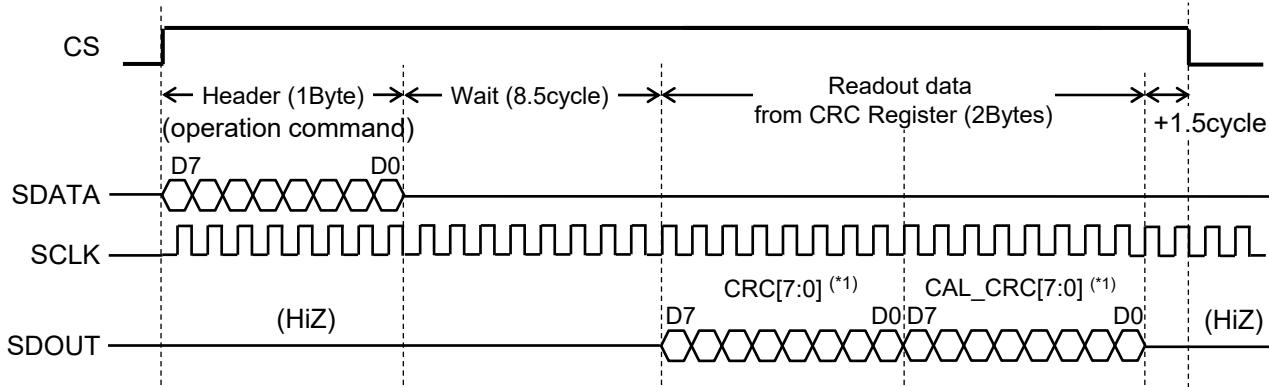


Note:

In case of "READ" operation, SDATA inputs except for Header are ignored. (CRC error detection is disabled)

■ Access to CRC & ERROR Register with SPI

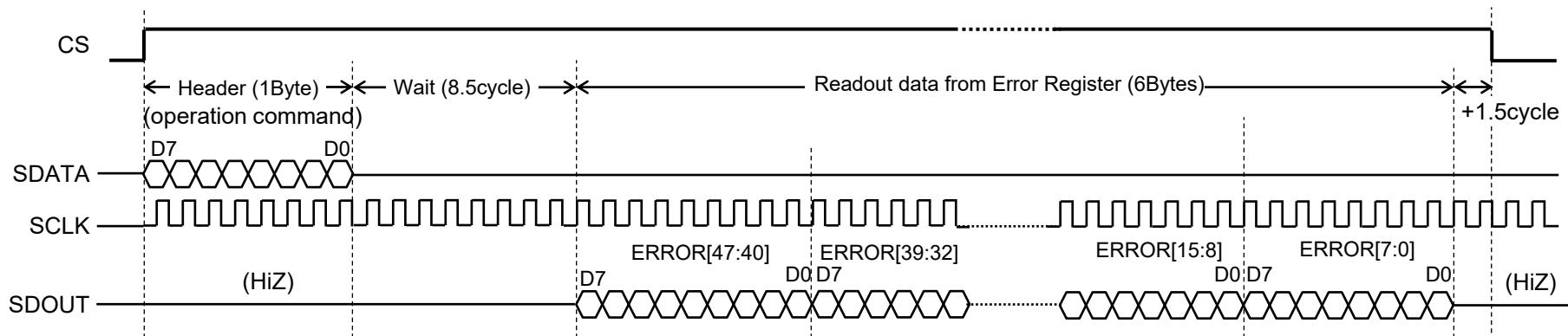
◆ Read from CRC Register



Note:

*1: CRC[7:0] and CAL_CRC[7:0] is the received CRC data and its calculated CRC data in previous “WRITE” operation.

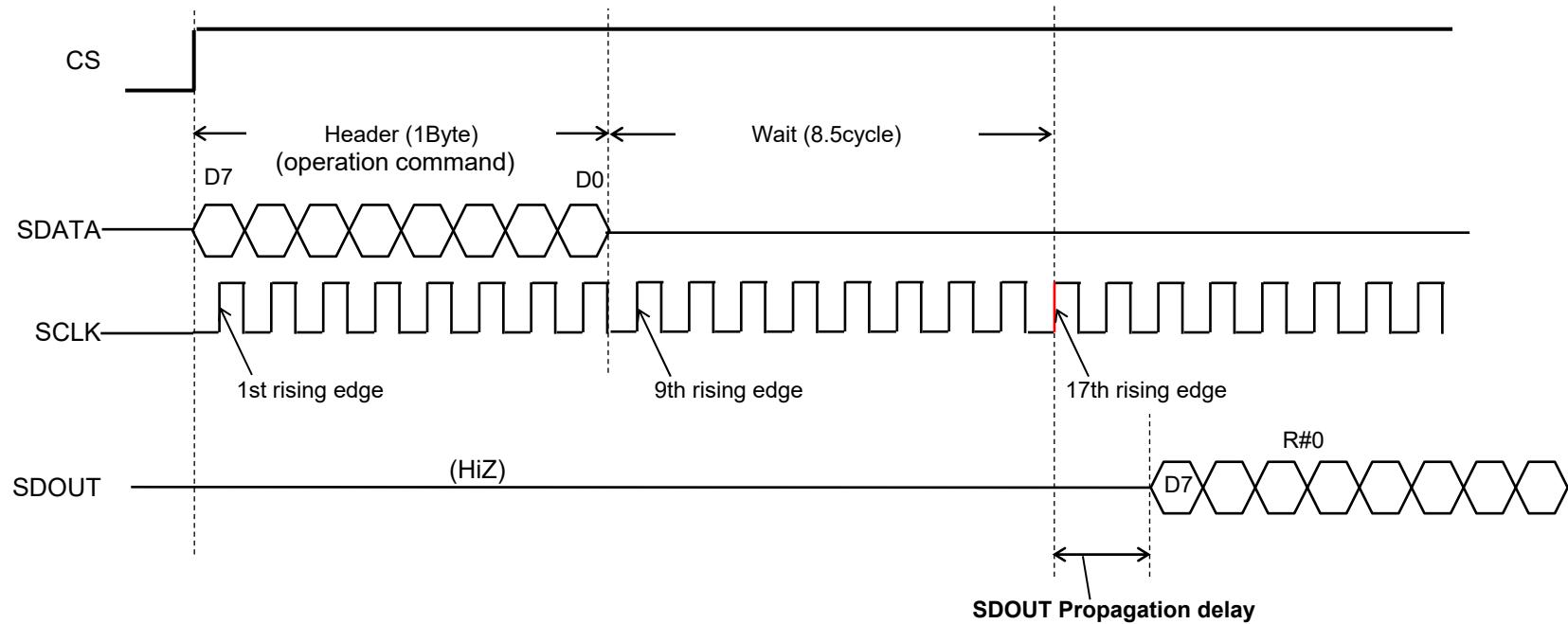
◆ Read from control Register



■ Definition of SDOUT Propagation Delay

The SDOUT propagation delay is defined as the time from the 17th rising edge of SCLK until the data comes out of SDOUT.
 (Independent of SCLK rate.)

◆ Read from Register and Memory



■ Operation Mode

◆ Operation mode

section	EN	CS_FLAG	TRIG	Tx-pattern	DRV_SEL(y)	Access to Ch(x) DAC Memory		Access to Ch(x) 3LP Memory		Access to Register (control)		Ch(x) DAC	Ch(x) 3LP Data	Operation mode	
						Write	Read	Write	Read	Write	Read				
A	0	0	0	none	*	x	x	x	x	x	x	x	O(*1)	Rx(TRSW control with 3LP data)	
B					Gen.	0	x	x	x	x	x	x	O(*1)	3LP Tx	
C					Gen.	1	x	x	x	x	x	x	O(*1)	DAC Tx	
D	0	0	1	none	*	x	x	x	x	x	x	x	x	Reset by TRIG	
E	0	1	0	none	*	O	O	O	O	O	O	x	x	O(*1)	Access to Memory or Register during Rx
F					Gen.	0	O	O	x (*2)	O	O	O	x	O(*1)	Access to Memory or Register during 3LP Tx
G					Gen.	1	x (*2)	x (*2)	O	O	O	O	O(*1)	x	x
-	0	1	1	none	*	O	O	O	O	O	O	x	x	x	Error[6] condition, N/A (*3)
H	1	0	*	none	0	x	x	x	x	x	x	x	x	x	Chip disabled
J	1	1	0	none	0	O	O	O	O	x (*4)	O	x	x	x	Access to Memory or Register during chip disabled
-	1	1	1	none	0	O	O	O	O	O	O	x	x	x	Error[6] condition, N/A (*3)

O : available, x : not available, $CS_FLAG = CS \cdot \overline{SPI_OFF}$

SPI_OFF is the bias control of LVDS Receiver in SPI for power saving. (0:bias on, 1:bias-off)

Suffix x (=0~7) corresponds to channel number, and Suffix y (=A/B) corresponds to the number of DRV_SEL.

DRV_SELA(or DRV_SELB) controls the ch0~3 (or ch4~7) operation.

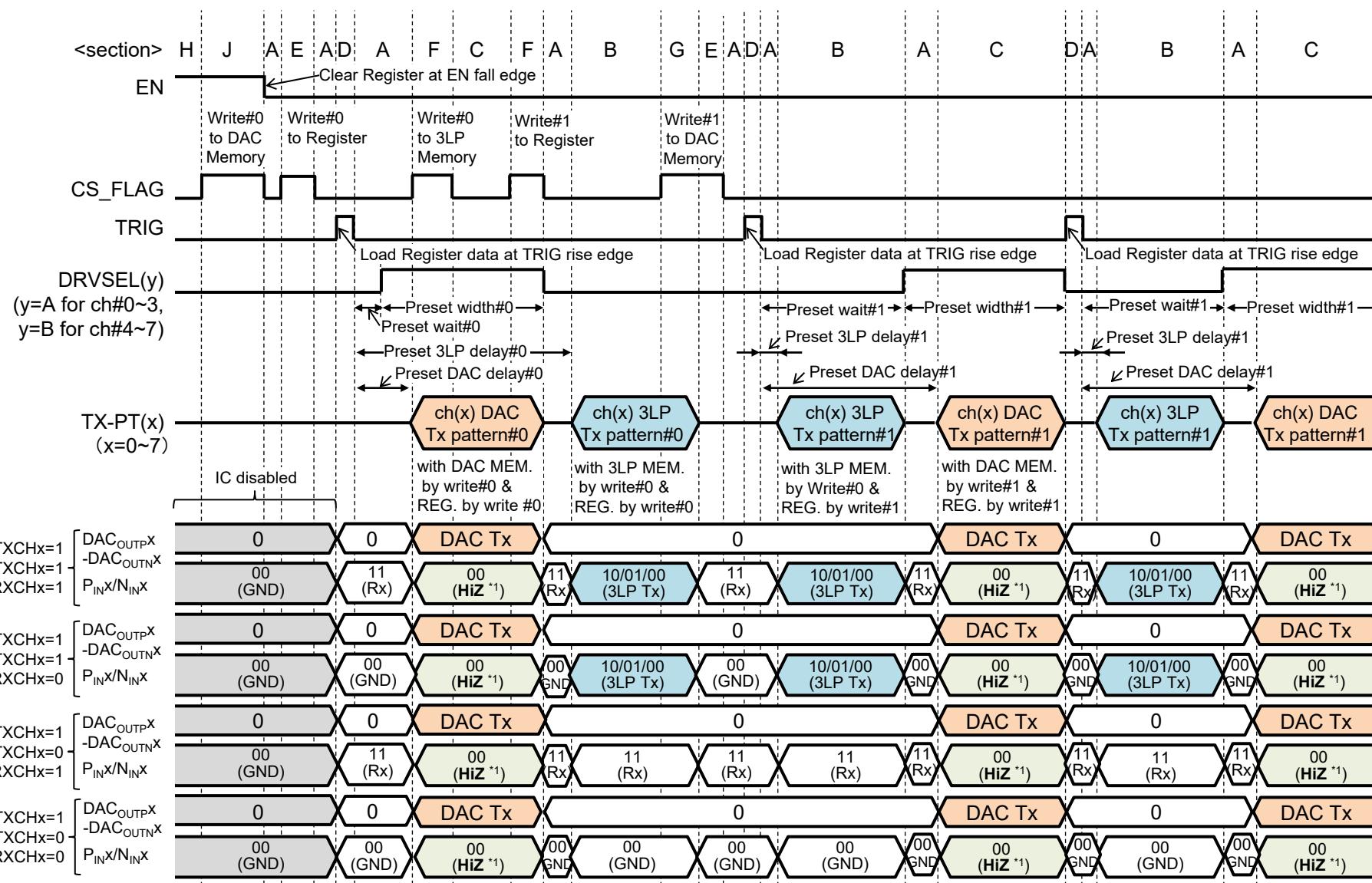
*1: Register parameter DACTXCHx, TLPTXCHx or RXCHx is necessary to be set "1".

*2: If CH(x) DAC Memory is accessed during CH(x) DAC Tx operation or CH(x) 3LP Memory is accessed during CH(x) 3LP Tx operation, ERROR[4] or ERROR[5] is set to "1" and Tx operation is stopped.

*3: "1" state of TRIG signal during CS_FLAG='1' is the error operation, so Tx operation is reset and its TRIG "1" is ignored.

*4: Register parameters are reset by fall edge of "EN".

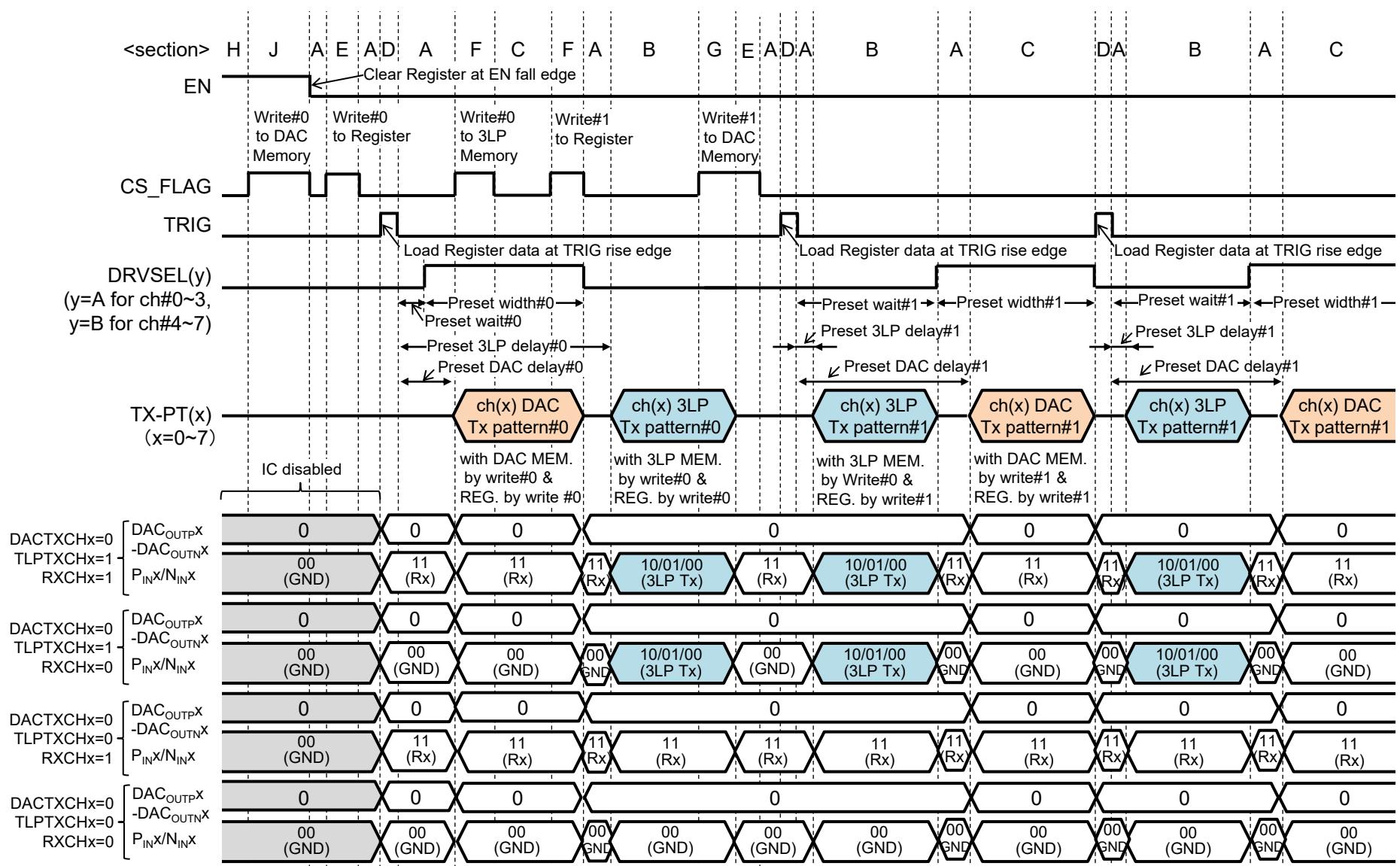
■ Operation Sequence Example



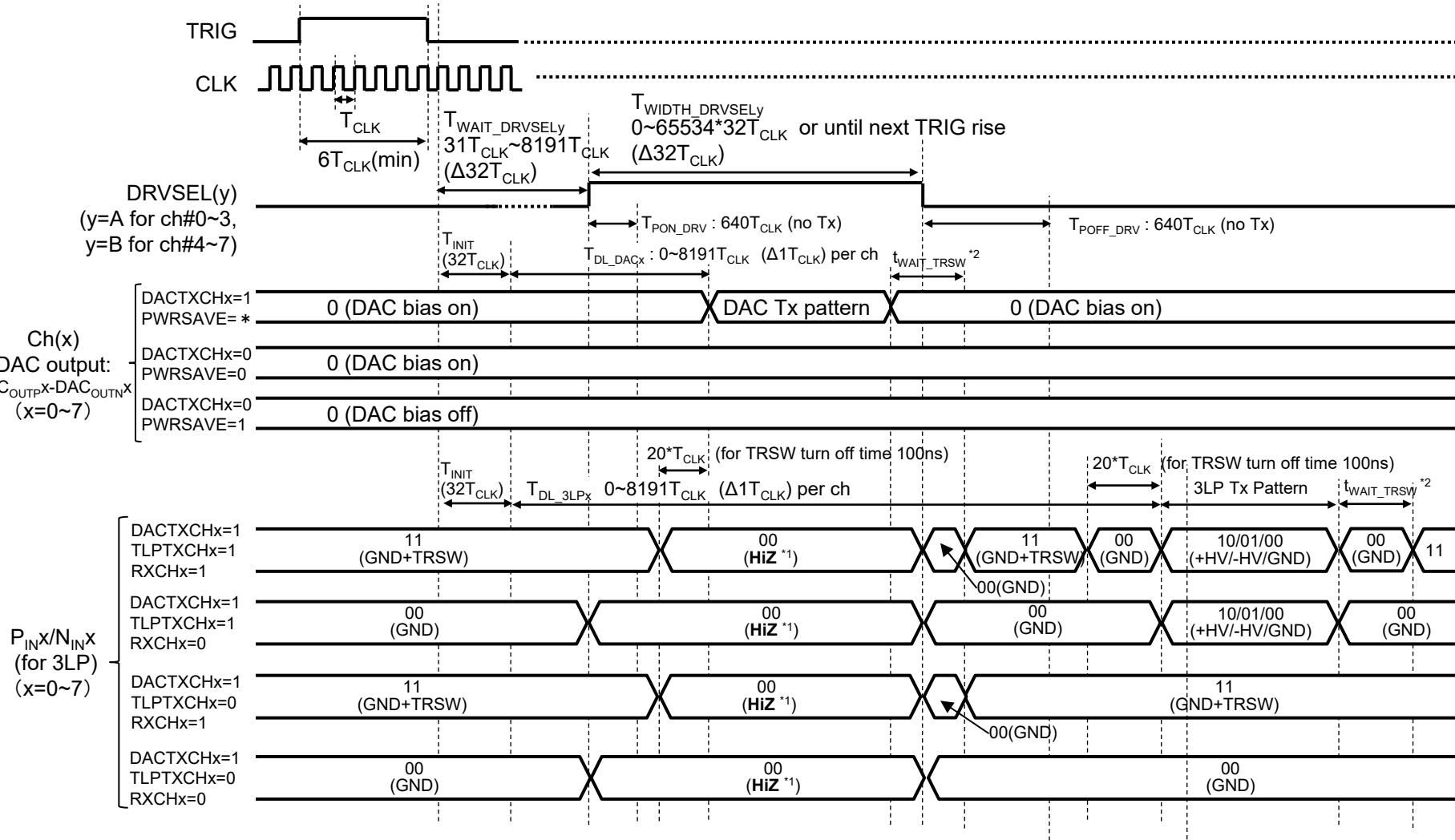
2bit output code of P_{INX}/N_{INX} corresponds to 3LP input code of "S-UM55L2".

*1: In 3LP Tx driver of "S-UM55L2", "HiZ" operation is assigned to "00" inputs during $DRVSEL = 1$.

■ Operation Sequence Example (continuation)



■ Tx Pattern Generation Timing Chart

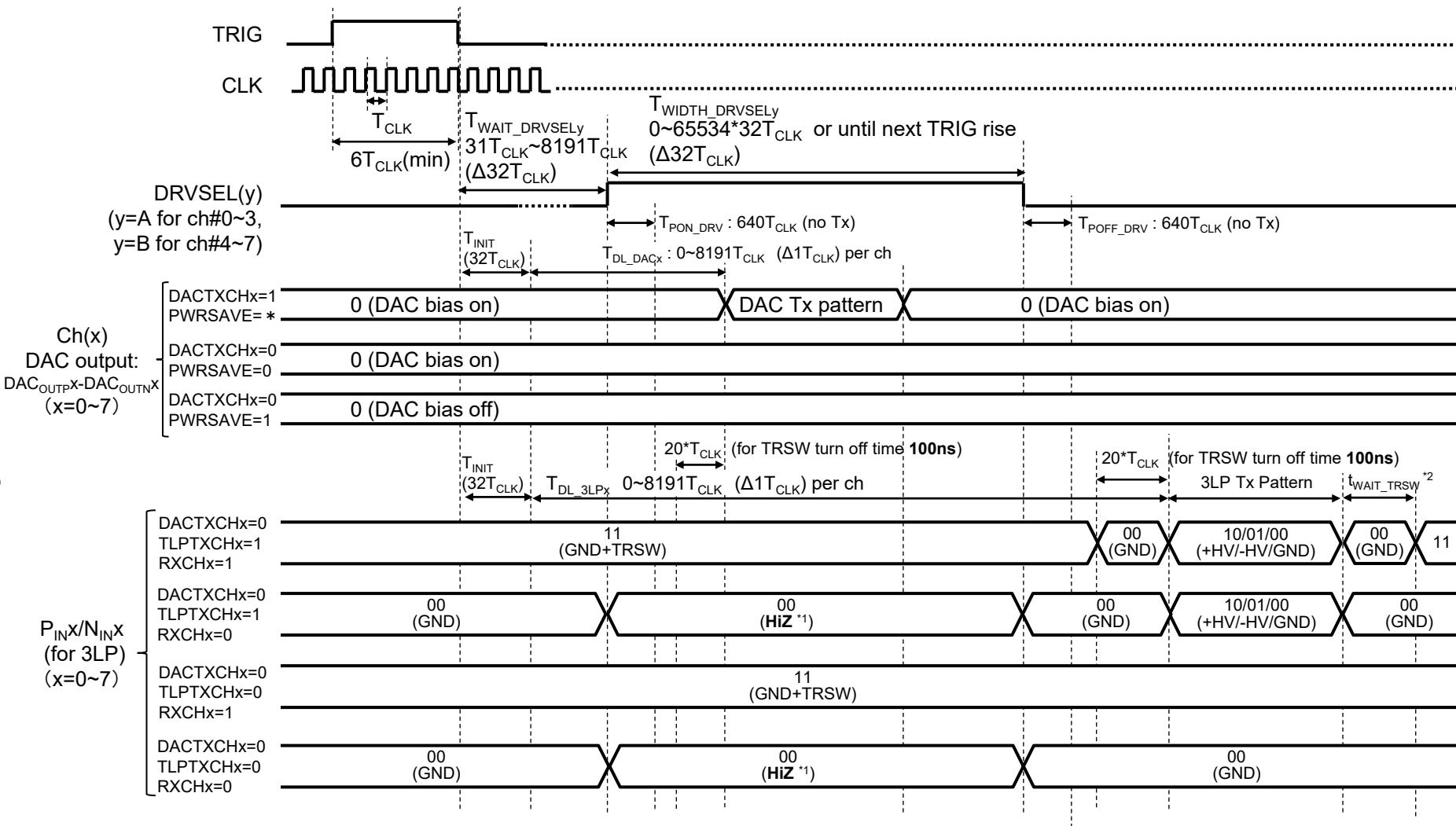


*1: In S-US55L2, 3LP driver outputs "HiZ" state during DRVSELY is "Hi" except both PINx and NINx is "Hi".

*2: t_{WAIT_TRSW} (0/80/120/160/200/240/280/320 T_{CLK}) is adjustable clamp time after transmission (per channel).

■ Tx Pattern Generation Timing Chart (continuation)

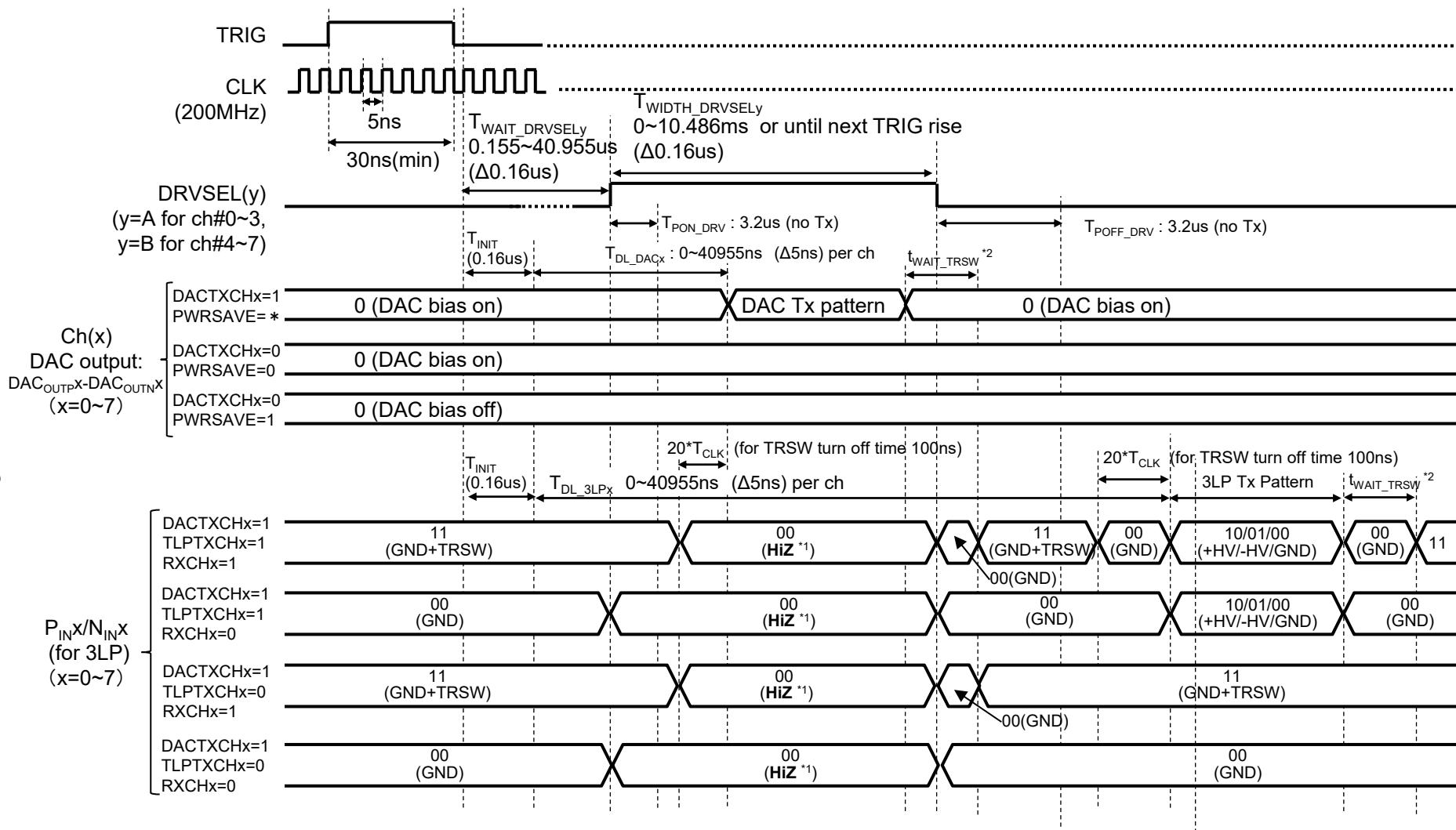
ABLIC Inc.



*1: In S-US55L2, 3LP driver outputs "HiZ" state during DRVSELy is "Hi" except both PINx and NINx is "Hi".

*2: t_{WAIT_TRSW} ($0/80/120/160/200/240/280/320T_{CLK}$) is adjustable clamp time after transmission (per channel).

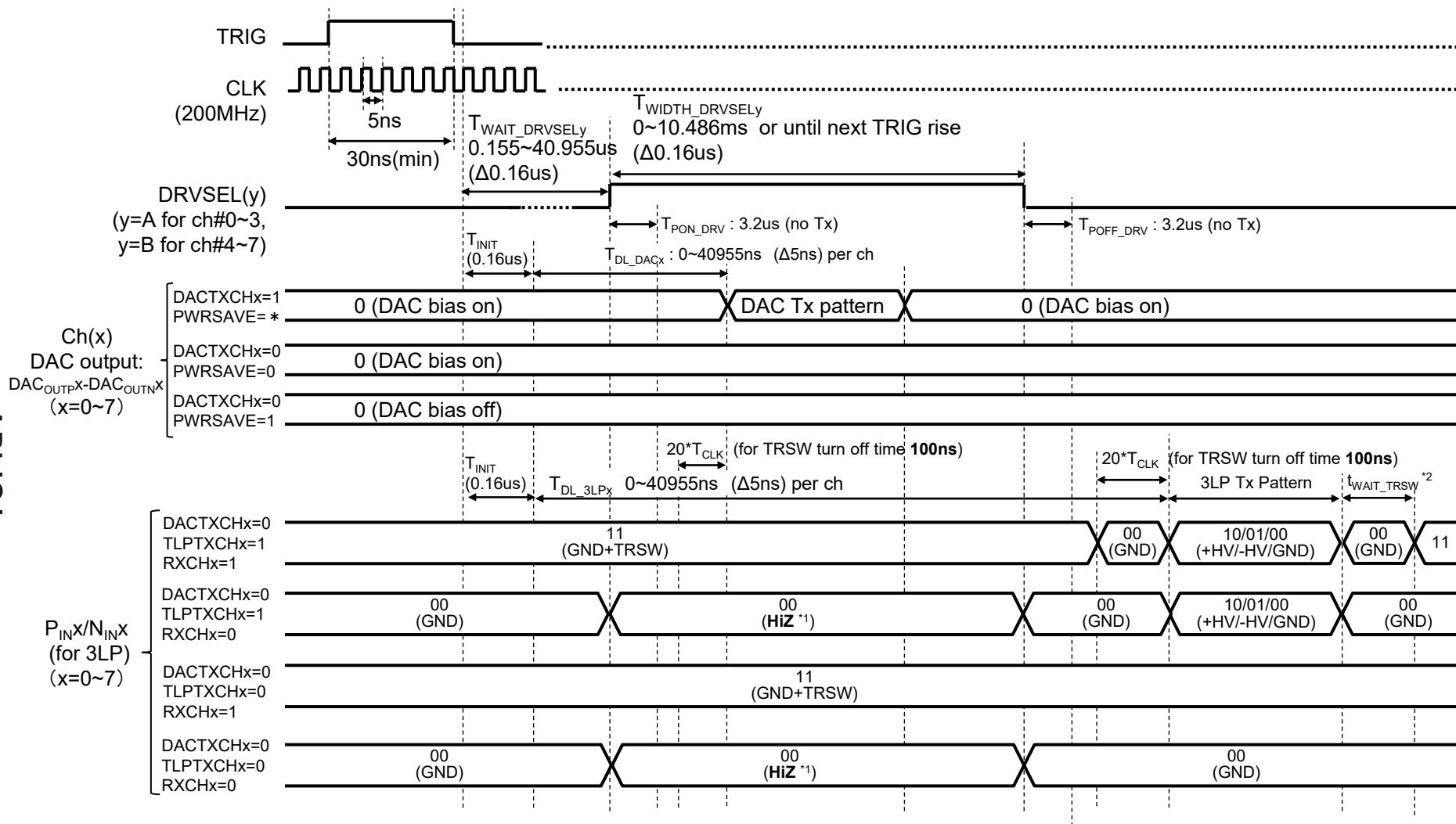
■ Tx Pattern Generation Timing Chart when use 200MHz CLK (1/2)



*1: In S-US55L2, 3LP driver outputs "HiZ" state during DRVSELy is "Hi" except both PINX and NINx is "Hi".

*2: t_{WAIT_TRSW} (0ns/400ns/600ns/800ns/1μs/1.2μs/1.4μs/1.6μs) is adjustable clamp time after transmission (per channel).

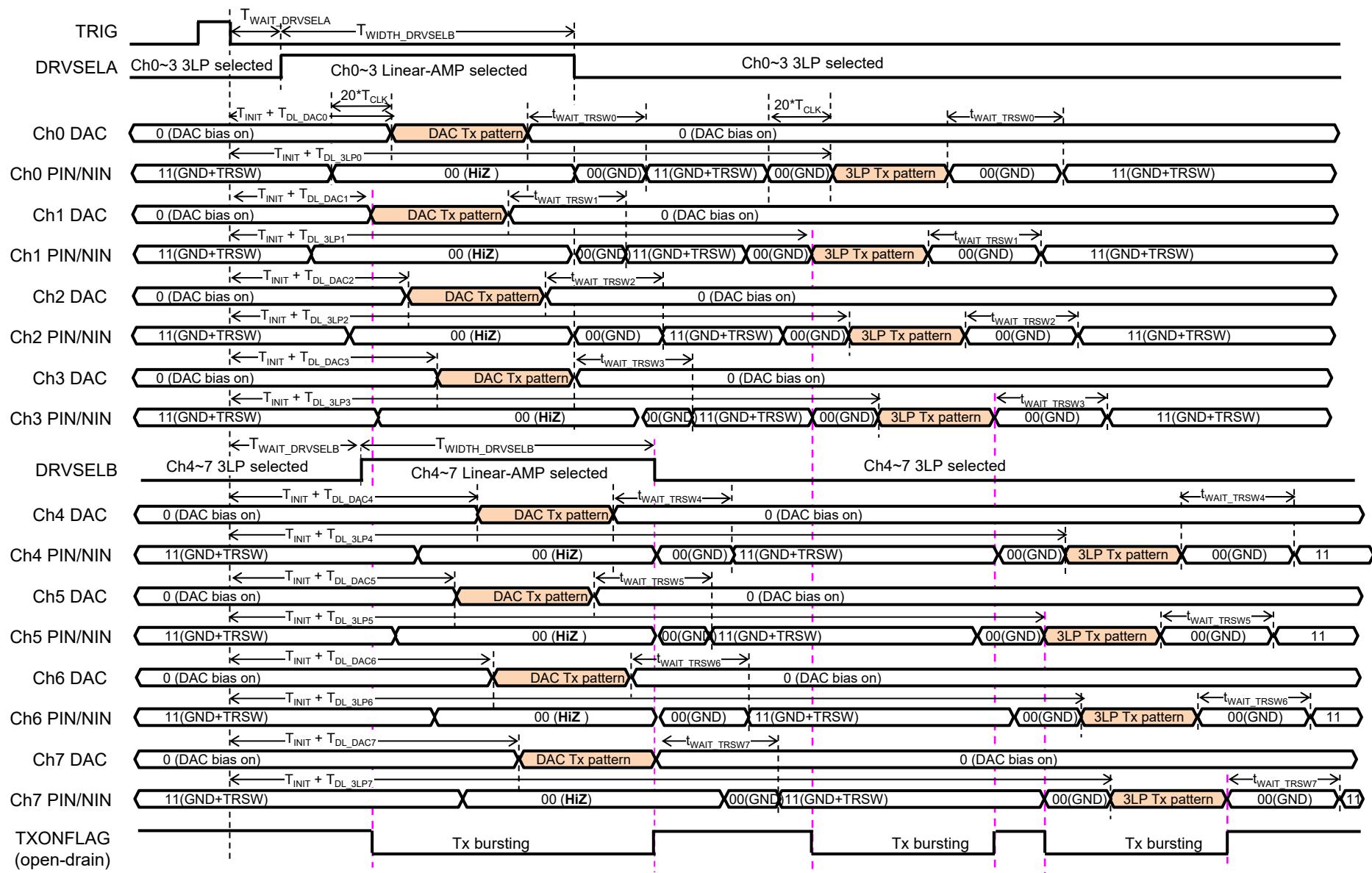
■ Tx Pattern Generation Timing Chart when use 200MHz CLK (2/2)



*1: In S-US55L2, 3LP driver outputs "HiZ" state during DRVSELy is "Hi" except both PINx and NINx is "Hi".

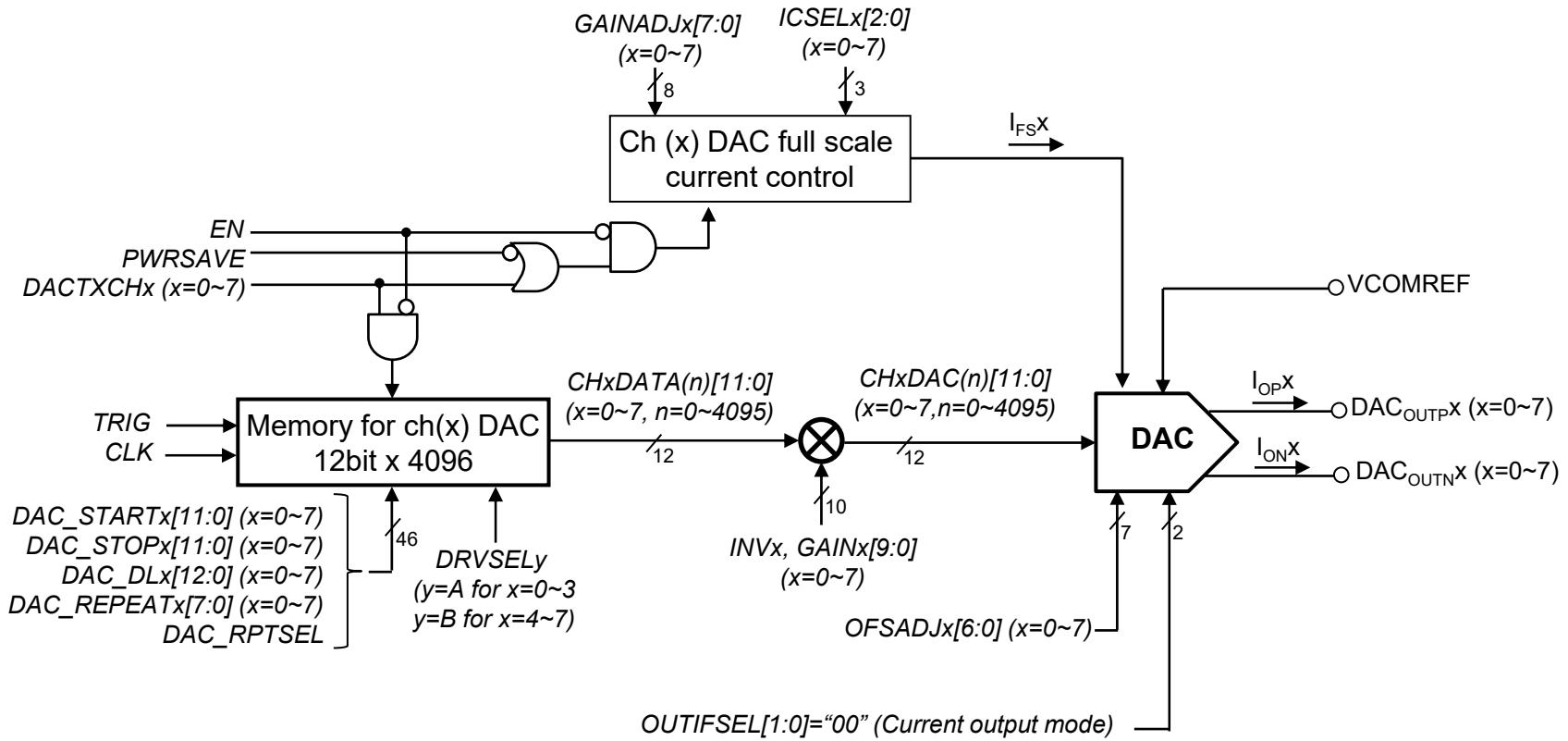
*2: t_{WAIT_TRSW} (0ns/400ns/600ns/800ns/1μs/1.2μs/1.4μs/1.6μs) is adjustable clamp time after transmission (per channel).

■ Tx Timing chart on “TXONFLAG”



Note: TXONFLAG is newly added open-drain indicator which is “OR” of each channel Tx bursting time.

■ DAC Block Diagram (Current Output mode)



■ DAC Equations & Parameter Definitions (Current mode)

◆ DAC Equations

$$I_{OPX} \text{ [mA]} = I_{FSX} * (2048 + CHxDAC(n)) / 4096 + I_{FSX} * (1 - OFSADJx[6]) * 3 * OFSADJx / 16384$$

$$I_{ONX} \text{ [mA]} = I_{FSX} * (2048 - CHxDAC(n)) / 4096 + I_{FSX} * OFSADJx[6] * 3 * OFSADJx / 16384$$

$$I_{OPX} - I_{ONX} \text{ [mA]} = 2 * I_{FSX} * CHxDAC(n) / 4096 + I_{FSX} * (1 - 2 * OFSADJx[6]) * 3 * OFSADJx / 16384$$

$$I_{FSX} \text{ [mA]} = 1.28 * G_{ADJ} * (ICSELx + 1)$$

$$G_{ADJ} = 1 + (6.25e-4) * (1 - 2 * GAINADJx[7]) * GAINADJx$$

$$CHxDAC(n) = G_Dx * CHxDATA(n)$$

$$G_Dx \text{ [V/V]} = (1 - 2 * INVx) * (GAINx + 1) / 1024$$

◆ Parameter Definitions

I_{OPX} [mA]: ch(x) DAC positive side output current from AV_{DD}

I_{ONX} [mA]: ch(x) DAC negative side output current from AV_{DD}

$I_{OPX} - I_{ONX}$ [mA]: ch(x) DAC differential output current

I_{FSX} [mA]: Selectable DAC full scale current (=1.2875mA~10.3mA, step=1.2875mA=25600*V_{BGR}/R_{BGR} at G_{ADJ}=1)

ICSELx(=0~7) : decimal number of 3bit full-scale current selector ICSELx[2:0]

G_{ADJ} [V/V]: Gain adjustment coefficient for DAC unit current compensation (=0.9603 ~1.0397, step=3.125e-4)

GAINADJx[7] (=0/1) : polarity bit of gain compensation data for ch(x) differential DAC output (0=positive, 1=negative)

GAINADJx(=0~127) : decimal number of gain compensation data for ch (x) differential DAC except for MSB (GAINADJ[6:0]).

CHxDAC(n) (-2047~2047) : decimal number of 12bit DAC inputs CHxDAC(n) [11:0] , MSB is polarity bit

CHxDATA(n) (-2047~2047) : decimal number of 12bit data CHxDATA(n) [11:0] form ch(x) DAC Memory(#n), MSB is polarity bit.

G_Dx [V/V]: Selectable digital gain for DAC (-1~1 except for 0, step=1/1024)

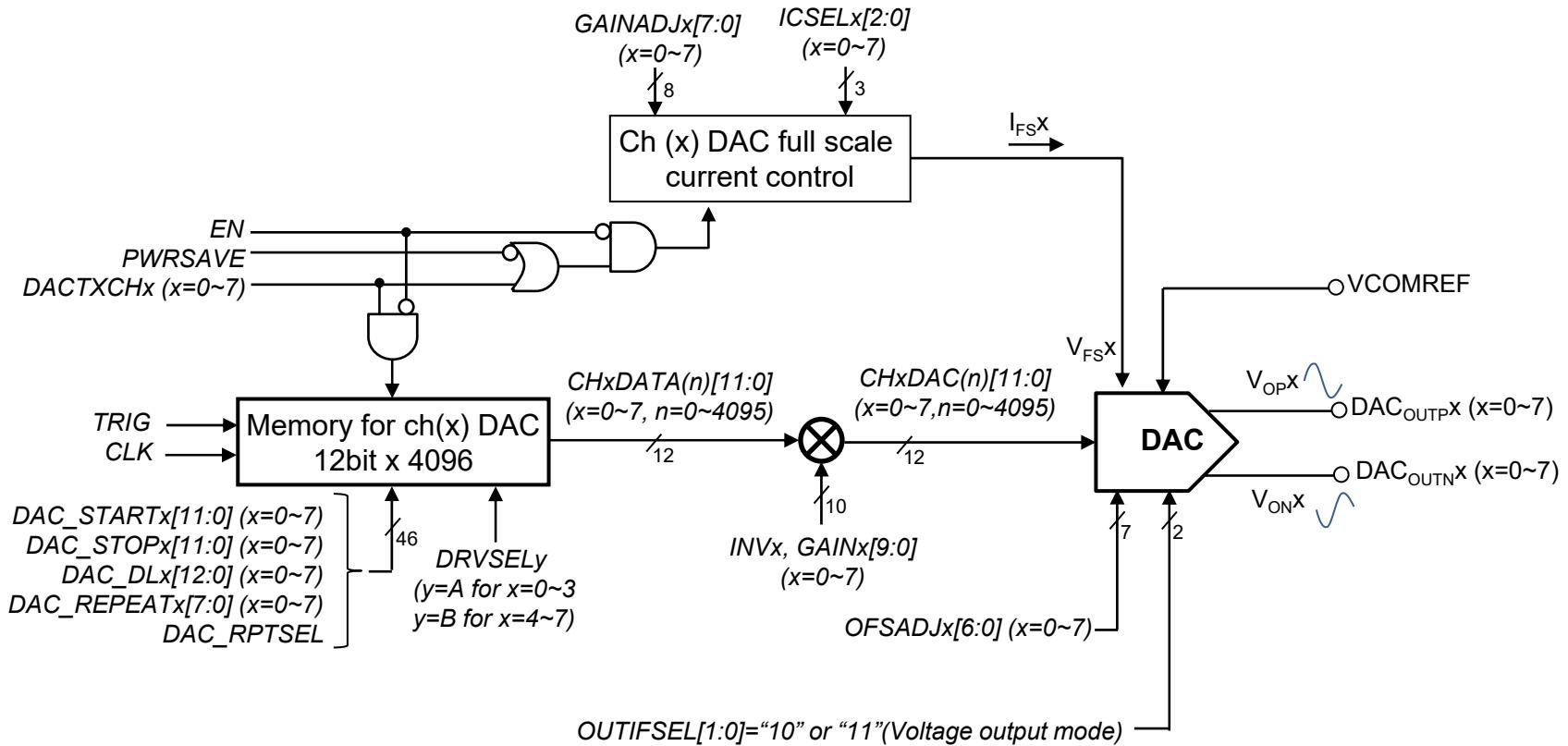
INVx (=0/1) : Inversion control of DAC/3LP output polarity. (0=Normal, 1=Inversion)

GAINx (=0~1023) is decimal number of GAINx[9:0]

OFSADJx[6] (=0/1) : polarity bit of offset compensation data for differential DAC output (0=positive, 1=negative),

OFSADJx (=0~63) : decimal number of offset compensation data for ch (x) differential DAC except for MSB (OFSADJx[5:0]).

■ DAC Block Diagram (Voltage Output mode)



■ DAC Equations & Parameter Definitions (Voltage mode)

◆ DAC Equations

$$V_{OPX} [V] = V_{FSX} * \{ +CHxDAC(n)/4096 + (1-OFSADJx[6])* 3* OFSADJx/16384 \} + VCOMREF$$

$$V_{ONX} [V] = V_{FSX} * \{ -CHxDAC(n)/4096 + OFSADJx[6]* 3* OFSADJx/16384 \} + VCOMREF$$

$$V_{OPX} - V_{ONX} [V] = V_{FSX} * \{ 2*CHxDAC(n)/4096 + (1-2*OFSADJx[6])* 3* OFSADJx/16384 \}$$

$$\begin{aligned} V_{FSX} [V] &= 0.074 * G_{ADJ} * (ICSELx+1) \quad @OUTIFSEL[1:0] = "10" \\ &\quad = 0.083 * G_{ADJ} * (ICSELx+1) \quad @OUTIFSEL[1:0] = "11" \end{aligned}$$

$$G_{ADJ} = 1 + (6.25e-4) * (1-2*GAINADJx[7]) * GAINADJx$$

$$CHxDAC(n) = G_Dx * CHxDATA(n)$$

$$G_Dx [V/V] = (1-2*INVX) * (GAINx+1)/1024$$

◆ Parameter Definitions

V_{OPX} [V]: ch(x) DAC positive side output voltage

V_{ONX} [V]: ch(x) DAC negative side output voltage

$V_{OPX} - V_{ONX}$ [V]: ch(x) DAC differential output voltage

V_{FSX} [mA]: Selectable DAC full scale voltage

= 0.077V~0.616V, step=0.077V @ $G_{ADJ}=1$, OUTIFSEL='10'

= 0.083V~0.664V, step=0.083V @ $G_{ADJ}=1$, OUTIFSEL='11'

ICSELx(=0~7) : decimal number of 3bit full-scale current selector ICSELx[2:0]

G_{ADJ} [V/V]: Gain adjustment coefficient for DAC unit current compensation (=0.9603 ~1.0397, step=3.125e-4)

GAINADJx[7] (=0/1) : polarity bit of gain compensation data for ch(x) differential DAC output (0=positive, 1=negative)

GAINADJx(=0~127) : decimal number of gain compensation data for ch (x) differential DAC except for MSB (GAINADJ[6:0]).

CHxDAC(n) (-2047~2047) : decimal number of 12bit DAC inputs CHxDAC(n) [11:0] , MSB is polarity bit

CHxDATA(n) (-2047~2047) : decimal number of 12bit data CHxDATA(n) [11:0] form ch(x) DAC Memory(#n), MSB is polarity bit.

G_Dx [V/V]: Selectable digital gain for DAC (-1~1 except for 0, step=1/1024)

INVx (=0/1) : Inversion control of DAC/3LP output polarity. (0=Normal, 1=Inversion)

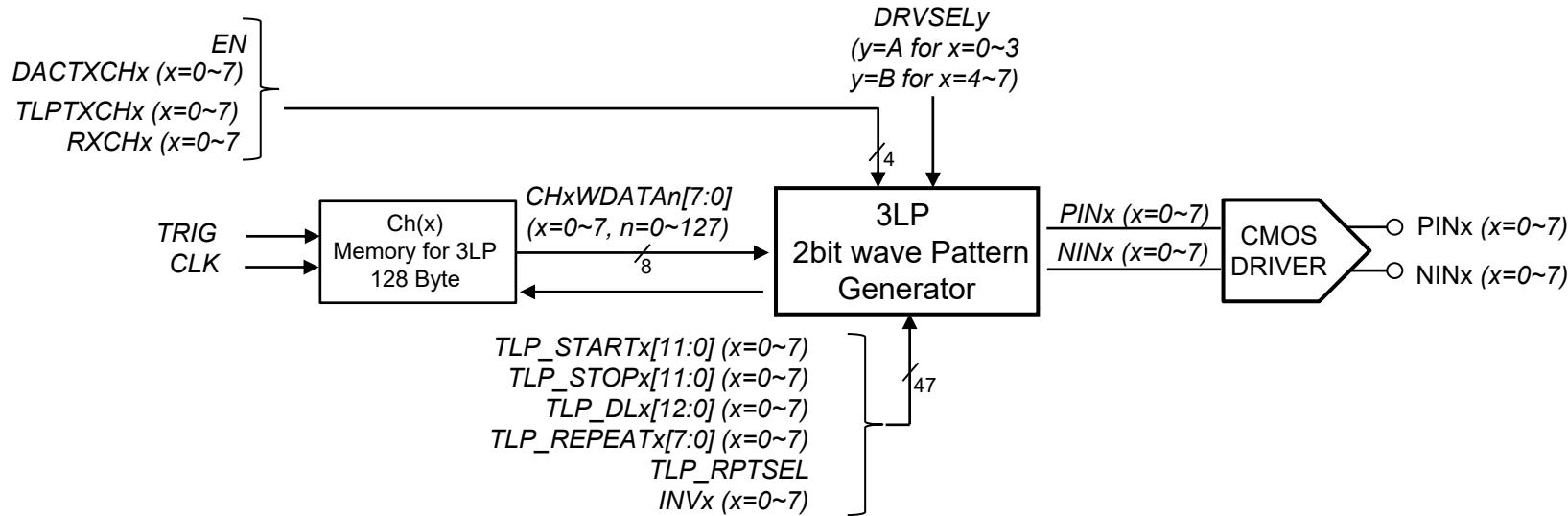
GAINx (=0~1023) is decimal number of GAINx[9:0]

OFSADJx[6] (=0/1) : polarity bit of offset compensation data for differential DAC output (0=positive, 1=negative),

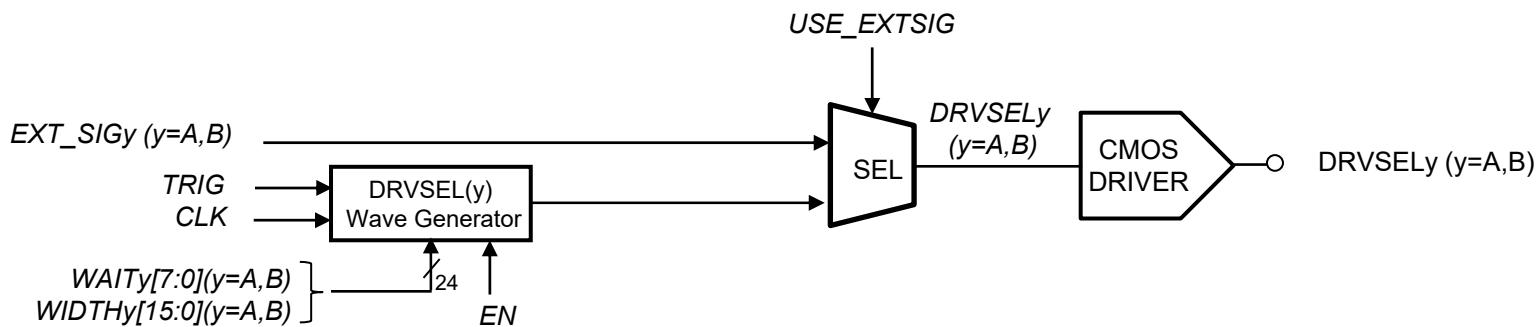
OFSADJx (=0~63) : decimal number of offset compensation data for ch (x) differential DAC except for MSB (OFSADJx[5:0]).

■ 3LP DATA & DRVSEL Generator Block Diagram

◆ 3LP DATA Generator



◆ DRVSEL Signal Generator



■ DAC Memory MAP

Ch#x (x=0~7) DAC_MEM.#	D11 (MSB)	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0 (LSB)	Default	W/R
0													-	W/R
1													-	W/R
2													-	W/R
3													-	W/R
:													..	:
n													-	W/R
:													..	:
4092													-	W/R
4093													-	W/R
4094													-	W/R
4095													-	W/R

In CH#x DAC Memory Map, each 12bit code CHxDATAn[11:0] corresponds to read-out data (CHxDATAn) in 1 clock cycle from CH#x DAC Memory#n.

Suffix “x” corresponds to channel number (x=0~7)

Suffix “n” corresponds to Memory number of 12bit code (n=0~4095)

CHxDATAn(=-2047~2047) is a decimal value of CHxDATAn[11:0].

Where, CHxDATAn[11] is polarity bit (0:+, 1:-) and decimal number of CHxDATAn[10:0](=0~2047) expresses the absolute value.

Note: Memory for DAC has no reset sequence.

■ 3LP Data Memory MAP

CH#x (x=0~7) 3LP MEM.#	D7 (MSB)	D6	D5	D4	D3	D2	D1	D0 (LSB)	Default	W/R
0	CHxCODE0[1:0]							CHxWIDTH0[5:0]	00000000	W/R
1	CHxCODE1[1:0]							CHxWIDTH1[5:0]	00000000	W/R
2	CHxCODE2[1:0]							CHxWIDTH2[5:0]	00000000	W/R
3	CHxCODE3[1:0]							CHxWIDTH3[5:0]	00000000	W/R
:	:							:	:	:
n	CHxCODEn[1:0]							CHxWIDTHn[5:0]	00000000	W/R
:	:							:	:	:
124	CHxCODE124[1:0]							CHxWIDTH124[5:0]	00000000	W/R
125	CHxCODE125[1:0]							CHxWIDTH125[5:0]	00000000	W/R
126	CHxCODE126[1:0]							CHxWIDTH126[5:0]	00000000	W/R
127	CHxCODE127[1:0]							CHxWIDTH127[5:0]	00000000	W/R

In CH#x 3LP DATA Memory Map, each 1-byte code consists of upper 2-bit CHxCODEn[1:0] and lower 6-bit CHxWIDTHn[5:0].

Suffix “x” corresponds to channel number (x=0~7)

Suffix “n” corresponds to 1-byte Memory number (n=0~127)

CHxCODEn[1:0] stands for an output state for 3LP Tx burst as shown in Truth Table.

CHxWIDTHn[5:0] expresses the pulse width (T_{WIDTH}) which is calculated as follows.

$$T_{CHxWIDTHn} [ns] = T_{CLK} * (CHxWIDTHn + 2)$$

Where, T_{CLK} is the CLKP/CLKN clock period and CHxWIDTHn(=0~63) is decimal number of CHxWIDTHn[5:0].

In case of 200MHz clock

$$T_{CLK} = 5\text{ns} \text{ and } T_{CHxWIDTHn} [ns] \text{ is } 10\text{ns} \sim 325\text{ns} \text{ (5ns step)}$$

Memory for 3LP data is reset by power-on transition of VLL.

■ Register Function (1)

Register Parameter		Function
PDSEL[1:0]	Common	DAC OUTPUT pull-down control during DAC bias-off 00: Open, 01: Not used, 10: pull-down to GND with 100Ω, 11: pull-down to VCOMREF with 40kΩ
OUTIFSEL[1:0]	Common	DAC OUTPUT mode Selection 00: current output, 01: Not available, 10: voltage output ($R_o=14\Omega$), 11: voltage output ($R_o=2\Omega$)
USE_EXTSIG	Common	0: use internal signal for DRVSELA/B, 1: use external signal as DRVSELA/B
PWRSAVE	Common	0: DAC bias is on at disable state, 1: DAC bias is off at disable state
DAC_RPTSEL	Common	Multiplying factor selection for DAC_REPEATx[7:0] / TLP_REPEATx[7:0] (0=1, 1=16)
TLP_RPTSEL	Common	Multiplying factor selection for DAC_REPEATx[7:0] / TLP_REPEATx[7:0] (0=1, 1=16)
DACTXCHx (x=0~7)	/channel	Enable/Disable control of DAC Outputs (DACOUTPx/DACOUTNx at CHx) (0:disabled, 1:enable) In case of PWRSAVE="1", ch(x) DAC is also bias-off at DACTXCHx="0"
TLPTXCHx (x=0~7)	/channel	Enable/Disable control for 3LP Tx operation at CHx (0: PINx,NINx ="0,0" , 1: PINx,NINx ="0,0" or "1,0" or "0,1" during Tx operation)
RXCHx (x=0~7)	/channel	Enable/Disable control for Rx operation (TRSW of TLP ON/Off) at CHx (0: PINx,NINx ="0,0" , 1: PINx,NINx ="1,1" during Rx operation)
WAITy[7:0] (y=A/B)	/4channel	DRVSELY wait time from TRIG fall : $32 \cdot T_{CLK} \cdot WAITy + 31 \cdot T_{CLK}$, WAITy(=0~255) is decimal number of WAITy[7:0]
WIDTHy[15:0] (y=A/B)	/4channel	DRVSELY Hi duration time ($T_{WIDTH_DRVSELY}$) WIDTHy[15:0]= 1111111111111111 : keep Hi until next Trig rise edge or reset with "EN" else $T_{WIDTH_DRVSELY} = 32 \cdot T_{CLK} \cdot WIDTHy$, WIDTHy(=0~65535) is decimal number of WIDTHy[15:0]

Note: Register parameter hatched by brown color  is latched to F/F with TRIG rise edge.

■ Register Function (2)

Register Parameter		Function
DAC_STARTx[11:0] (x=0~7)	/channel	Start address (0~4095) of the DAC Memory
DAC_STOPx[11:0] (x=0~7)	/channel	Stop address (0~4095) of the DAC Memory
DAC_REPEATx[7:0]	/channel	Repeat counts control of DAC Tx waveform pattern generation for ch(x) (x=0~7) DACx_REPEAT(=0~255) is decimal number of DAC_REPEATx[7:0] DACx_REPEAT=0, Repeat counts=1 DACx_REPEAT=1~254, Repeat counts=1*DAC_REPEATx or 16*DAC_REPEATx (Multiplying factor (1 or 16) is selectable with DAC_RPTSEL) DACx_REPEAT=255, Repeat counts = continuous wave (CW) CW is stopped by next TRIG rise edge or SPI access
DAC_DLx[12:0] (x=0~7)	/channel	Chx Tx delay from TRIG fall edge : $32*T_{CLK} + T_{CLK} * DAC_DLx$, (DAC_DLx = 0~8191) $\times 1$
ICSELx[2:0] (x=0~7)	/channel	DAC unit current (I_C) , $I_C(=0.3125\sim2.5)$ [uA] = $0.3125 * (1+ICSELx)$ ICSELx(=0~7) is decimal number of ICSELx[2:0]
GAINx[9:0] (x=0~7)	/channel	DAC Digital Gain Control at CHx ($G_{DIG}x$), $G_{DIG}x(=1/1024\sim1) = (1+GAINx)/1024$ GAINx(=0~1023) is decimal number of GAINx[9:0]
ACT_GAINADJx (x=0~7)	/channel	Option for GAINADJx[7:0] (0: Register GAINADJx[7:0] is not available, 1: Register GAINADJx[7:0] is available)
GAINADJx[7:0] (x=0~7)	/channel	DAC gain adjustment coefficient (G_{ADJ}): 0.9206 ~ 1.0794 (step=6.25e-4) $G_{ADJ} = 1 + (1 - 2 * GAINADJx[7]) * (6.25e-4) * GAINADJx$ GAINADJx[7](=0/1) is polarity bit, GAINADJx(=0~127) is decimal number of GAINADJx[6:0]
ACT_OFSADJx (x=0~7)	/channel	Option for OFSADJx[6:0] (0: Register OFSADJx[6:0] is not available, 1: Register OFSADJx[6:0] is available)
OFSADJx[6:0] (x=0~7)	/channel	DAC differential current offset ($\Delta I_{DACP}x - I_{DACP}x$) adjustment : $-63*I_C/4 \sim +63*I_C/4$, step= $I_C/4$ OFSADJx[6] =0: OFSADJx*I_C/4 is added to $I_{DACP}x$, OFSADJx[6] =1: OFSADJx*I_C/4 is added to $I_{DACP}x$. OFSADJx(=0~63) is decimal number of OFSADJx[5:0]

Note: Register parameter hatched by brown color  is latched to F/F with TRIG rise edge.

※1 . In case of USE_EXTSIG=0 , DAC_DLx=0~639(decimal number) cannot be used due to restrictions with DRVSEL.

■ Register Function (3)

Register Parameter		Function
TLP_STARTx[6:0] (x=0~7)	/channel	Start address (0~127) of the 3LP Memory
TLP_STOPx[6:0] (x=0~7)	/channel	Stop address (0~127) of the 3LP Memory
TLP_REPEATx[7:0]	/channel	Repeat counts control of Tx waveform pattern generation for ch(x) (x=0~7) TLP_REPEATx(=0~255) is decimal number of TLP_REPEATx[7:0] TLP_REPEATx=0 : Repeat counts=1 TLP_REPEATx=1~254 : Repeat counts=1*TLP_REPEATx or 16*TLP_REPEATx (Multiplying factor (1 or 16) is selectable with TLP_RPTSEL.) TLP_REPEATx=255 : Repeat counts = continuous wave (CW) CW is stopped by next TRIG rise edge or SPI access
TLP_DLx[12:0] (x=0~7)	/channel	Chx Tx delay from TRIG fall edge : $32 \cdot T_{CLK} + T_{CLK} \cdot TLP_DLx$, ($TLP_DLx = 0 \sim 8191$)
INVx	/channel	Polarity inversion of generating DAC/3LP Tx waveform pattern (0:Normal, 1: Inversion)
TRSW_WAITx[2:0]	/channel	clamp (TRSW-On wait) time after transmission "000"=0, "001"=80*T _{CLK} , "010"=120*T _{CLK} , "011"=160*T _{CLK} , "100"=200*T _{CLK} , "101"=240*T _{CLK} , "110"=280*T _{CLK} , "111"=320*T _{CLK}

Note: Register parameter hatched by brown color ■ is latched to F/F with TRIG rise edge.

■ Control Register Map (1)

Function	REG.#	D7 (MSB)	D6	D5	D4	D3	D2	D1	D0 (LSB)	Default	W/R
Common setting	0	PDSEL[1:0]		OUTIFSEL[1:0]		USE_EXTSIG	PWRSAVE	DAC_RPTSEL	TLP_RPTSEL	00000000	W/R
Active ch selection	1	DACTXCH0	DACTXCH1	DACTXCH2	DACTXCH3	DACTXCH4	DACTXCH5	DACTXCH6	DACTXCH7	00000000	W/R
	2	TLPTXCH0	TLPTXCH1	TLPTXCH2	TLPTXCH3	TLPTXCH4	TLPTXCH5	TLPTXCH6	TLPTXCH7	00000000	W/R
	3	RXCH0	RXCH1	RXCH2	RXCH3	RXCH4	RXCH5	RXCH6	RXCH7	00000000	W/R
Reserved	4	RESERVEDC[15:8]								00000000	W/R
	5	RESERVEDC[7:0]								00000000	W/R
DRVSEL#A Setting	6	WAITA[7:0]								00000000	W/R
	7	WIDTHA[15:8]								00000000	W/R
	8	WIDTHA[7:0]								00000000	W/R
DRVSEL#B Setting	9	WAITB[7:0]								00000000	W/R
	10	WIDTHB[15:8]								00000000	W/R
	11	WIDTHB[7:0]								00000000	W/R

Note: Register parameter hatched by brown  is re-latched into F/F with TRIG rise edge.

■ Control Register Map (2)

Function	REG.#	D7 (MSB)	D6	D5	D4	D3	D2	D1	D0 (LSB)	Default	W/R
Ch#0 DAC Setting	12					DAC_START0[11:4]				00000000	W/R
	13			DAC_START0[3:0]			DAC_STOP0[11:8]			00000000	W/R
	14					DAC_STOP0[7:0]				00000000	W/R
	15					DAC_REPEAT0[7:0]				00000000	W/R
	16					DAC_DL0[12:5]				00000000	W/R
	17			DAC_DL0[4:0]				ICSEL0[2:0]		00000000	W/R
	18	ACT_GAINADJ0		TRSW_WAIT0[2:0]		RESERVED0[5:4]			GAIN0[9:8]	00000000	W/R
	19					GAIN0[7:0]				00000000	W/R
	20					GAIN_ADJ0[7:0]				00000000	W/R
	21	ACT_OFSADJ0				OFS_ADJ0[6:0]				00000000	W/R
Ch#0 3LP Data Setting	22	RESERVED0[3]				TLP_START0[6:0]				00000000	W/R
	23	RESERVED0[2]				TLP_STOP0[6:0]				00000000	W/R
	24					TLP_REPEAT0[7:0]				00000000	W/R
	25					TLP_DL0[12:5]				00000000	W/R
	26			TLP_DL0[4:0]		RESERVED0[1:0]			INV0	00000000	W/R
Ch#1 DAC Setting	27				DAC_START1[11:4]					00000000	W/R
	28			DAC_START1[3:0]			DAC_STOP1[11:8]			00000000	W/R
	29				DAC_STOP1[7:0]					00000000	W/R
	30				DAC_REPEAT1[7:0]					00000000	W/R
	31				DAC_DL1[12:5]					00000000	W/R
	32			DAC_DL1[4:0]			ICSEL1[2:0]			00000000	W/R
	33	ACT_GAINADJ1		TRSW_WAIT1[2:0]		RESERVED1[5:4]			GAIN1[9:8]	00000000	W/R
	34				GAIN1[7:0]					00000000	W/R
	35				GAIN_ADJ1[7:0]					00000000	W/R
	36	ACT_OFSADJ1			OFS_ADJ1[6:0]					00000000	W/R
Ch#1 3LP Data Setting	37	RESERVED1[3]			TLP_START1[6:0]					00000000	W/R
	38	RESERVED1[2]			TLP_STOP1[6:0]					00000000	W/R
	39				TLP_REPEAT1[7:0]					00000000	W/R
	40				TLP_DL1[12:5]					00000000	W/R
	41			TLP_DL1[4:0]		RESERVED1[1:0]			INV1	00000000	W/R

Note: Register parameter hatched by brown  is re-latched into F/F with TRIG rise edge.

■ Control Register Map (3)

Function	REG.#	D7 (MSB)	D6	D5	D4	D3	D2	D1	D0 (LSB)	Default	W/R
Ch#2 DAC Setting	42					DAC_START2[11:4]				00000000	W/R
	43			DAC_START2[3:0]			DAC_STOP2[11:8]			00000000	W/R
	44					DAC_STOP2[7:0]				00000000	W/R
	45					DAC_REPEAT2[7:0]				00000000	W/R
	46					DAC_DL2[12:5]				00000000	W/R
	47			DAC_DL2[4:0]				ICSEL2[2:0]		00000000	W/R
	48	ACT_GAINADJ2		TRSW_WAIT2[2:0]		RESERVED2[5:4]			GAIN2[9:8]	00000000	W/R
	49				GAIN2[7:0]					00000000	W/R
	50				GAIN_ADJ2[7:0]					00000000	W/R
	51	ACT_OFSADJ2			OFS_ADJ2[6:0]					00000000	W/R
Ch#2 3LP Data Setting	52	RESERVED2[3]			TLP_START2[6:0]					00000000	W/R
	53	RESERVED2[2]			TLP_STOP2[6:0]					00000000	W/R
	54				TLP_REPEAT2[7:0]					00000000	W/R
	55				TLP_DL2[12:5]					00000000	W/R
	56			TLP_DL2[4:0]		RESERVED2[1:0]			INV2	00000000	W/R
Ch#3 DAC Setting	57				DAC_START3[11:4]					00000000	W/R
	58		DAC_START3[3:0]			DAC_STOP3[11:8]				00000000	W/R
	59				DAC_STOP3[7:0]					00000000	W/R
	60				DAC_REPEAT3[7:0]					00000000	W/R
	61				DAC_DL3[12:5]					00000000	W/R
	62		DAC_DL3[4:0]			ICSEL3[2:0]				00000000	W/R
	63	ACT_GAINADJ3		TRSW_WAIT3[2:0]		RESERVED3[5:4]			GAIN3[9:8]	00000000	W/R
	64				GAIN3[7:0]					00000000	W/R
	65				GAIN_ADJ3[7:0]					00000000	W/R
	66	ACT_OFSADJ3			OFS_ADJ3[6:0]					00000000	W/R
Ch#3 3LP Data Setting	67	RESERVED3[3]			TLP_START3[6:0]					00000000	W/R
	68	RESERVED3[2]			TLP_STOP3[6:0]					00000000	W/R
	69				TLP_REPEAT3[7:0]					00000000	W/R
	70				TLP_DL3[12:5]					00000000	W/R
	71		TLP_DL3[4:0]		RESERVED3[1:0]				INV3	00000000	W/R

Note: Register parameter hatched by brown  is re-latched into F/F with TRIG rise edge.

■ Control Register Map (4)

Function	REG.#	D7 (MSB)	D6	D5	D4	D3	D2	D1	D0 (LSB)	Default	W/R
Ch#4 DAC Setting	72					DAC_START4[11:4]				00000000	W/R
	73			DAC_START4[3:0]			DAC_STOP4[11:8]			00000000	W/R
	74					DAC_STOP4[7:0]				00000000	W/R
	75					DAC_REPEAT4[7:0]				00000000	W/R
	76					DAC_DL4[12:5]				00000000	W/R
	77			DAC_DL4[4:0]				ICSEL4[2:0]		00000000	W/R
	78	ACT_GAINADJ4		TRSW_WAIT4[2:0]		RESERVED4[5:4]			GAIN4[9:8]	00000000	W/R
	79				GAIN4[7:0]					00000000	W/R
	80				GAIN_ADJ4[7:0]					00000000	W/R
	81	ACT_OFSADJ4			OFS_ADJ4[6:0]					00000000	W/R
Ch#4 3LP Data Setting	82	RESERVED4[3]				TLP_START4[6:0]				00000000	W/R
	83	RESERVED4[2]				TLP_STOP4[6:0]				00000000	W/R
	84				TLP_REPEAT4[7:0]					00000000	W/R
	85				TLP_DL4[12:5]					00000000	W/R
	86			TLP_DL4[4:0]		RESERVED4[1:0]			INV4	00000000	W/R
Ch#5 DAC Setting	87				DAC_START5[11:4]					00000000	W/R
	88			DAC_START5[3:0]			DAC_STOP5[11:8]			00000000	W/R
	89				DAC_STOP5[7:0]					00000000	W/R
	90				DAC_REPEAT5[7:0]					00000000	W/R
	91				DAC_DL5[12:5]					00000000	W/R
	92			DAC_DL5[4:0]		RESERVED5[2:0]				00000000	W/R
	93	ACT_GAINADJ5		TRSW_WAIT5[2:0]		RESERVED5[5:4]			GAIN5[9:8]	00000000	W/R
	94				GAIN5[7:0]					00000000	W/R
	95				GAIN_ADJ5[7:0]					00000000	W/R
	96	ACT_OFSADJ5			OFS_ADJ5[6:0]					00000000	W/R
Ch#5 3LP Data Setting	97	RESERVED5[3]				TLP_START5[6:0]				00000000	W/R
	98	RESERVED5[2]				TLP_STOP5[6:0]				00000000	W/R
	99				TLP_REPEAT5[7:0]					00000000	W/R
	100				TLP_DL5[12:5]					00000000	W/R
	101			TLP_DL5[4:0]		RESERVED5[1:0]			INV5	00000000	W/R

Note: Register parameter hatched by brown  is re-latched into F/F with TRIG rise edge.

■ Control Register Map (5)

Function	REG.#	D7 (MSB)	D6	D5	D4	D3	D2	D1	D0 (LSB)	Default	W/R
Ch#6 DAC Setting	102					DAC_START6[11:4]				00000000	W/R
	103			DAC_START6[3:0]			DAC_STOP6[11:8]			00000000	W/R
	104					DAC_STOP6[7:0]				00000000	W/R
	105					DAC_REPEAT6[7:0]				00000000	W/R
	106					DAC_DL6[12:5]				00000000	W/R
	107			DAC_DL6[4:0]				ICSEL6[2:0]		00000000	W/R
	108	ACT_GAINADJ6		TRSW_WAIT6[2:0]		RESERVED6[5:4]			GAIN6[9:8]	00000000	W/R
	109				GAIN6[7:0]					00000000	W/R
	110				GAIN_ADJ6[7:0]					00000000	W/R
	111	ACT_OFSADJ6			OFS_ADJ6[6:0]					00000000	W/R
Ch#6 3LP Data Setting	112	RESERVED6[3]				TLP_START6[6:0]				00000000	W/R
	113	RESERVED6[2]				TLP_STOP6[6:0]				00000000	W/R
	114				TLP_REPEAT6[7:0]					00000000	W/R
	115				TLP_DL6[12:5]					00000000	W/R
	116			TLP_DL6[4:0]		RESERVED6[1:0]			INV6	00000000	W/R
Ch#7 DAC Setting	117				DAC_START7[11:4]					00000000	W/R
	118			DAC_START7[3:0]		DAC_STOP7[11:8]				00000000	W/R
	119				DAC_STOP7[7:0]					00000000	W/R
	120				DAC_REPEAT7[7:0]					00000000	W/R
	121				DAC_DL7[12:5]					00000000	W/R
	122			DAC_DL7[4:0]		ICSEL7[2:0]				00000000	W/R
	123	ACT_GAINADJ7		TRSW_WAIT7[2:0]		RESERVED7[5:4]		GAIN7[9:8]		00000000	W/R
	124				GAIN7[7:0]					00000000	W/R
	125				GAIN_ADJ7[7:0]					00000000	W/R
	126	ACT_OFSADJ7			OFS_ADJ7[6:0]					00000000	W/R
Ch#7 3LP Data Setting	127	RESERVED7[3]			TLP_START7[6:0]					00000000	W/R
	128	RESERVED7[2]			TLP_STOP7[6:0]					00000000	W/R
	129				TLP_REPEAT7[7:0]					00000000	W/R
	130				TLP_DL7[12:5]					00000000	W/R
	131			TLP_DL7[4:0]		RESERVED7[1:0]			INV7	00000000	W/R

Note: Register parameter hatched by brown  is re-latched into F/F with TRIG rise edge.

■ CRC & Error Register function (1)

Register parameter	Function
CRC[7:0]	Transferred 8bit CRC Data in last SPI Write operation CRC initial value = 00000000 CRC polynomial equation is $X^8+X^5+X^4+1$
CAL_CRC[7:0]	Calculated CRC values with transferred SDATA in last SPI Write operation
ERROR[47:40]	Memory address error for ch#x (x=0~7) 3LP data. (Start and Stop address is same when "TRIG" becomes high.) If Error has occurred in ch(x), Register bit ERROR[8x+40] is set to "1" and "FAULT" pin becomes to "0" until ERROR[8x+40] is cleared. Error[8x+40] is cleared with "EN" fall edge or setting Memory address for ch#x 3LP data properly.
ERROR[39:32]	Memory address error for ch#x (x=0~7) DAC. (Start and Stop address is same when "TRIG" becomes high.) If Error has occurred in ch(x), Register bit ERROR[8x+32] is set to "1" and "FAULT" pin becomes to "0" until ERROR[8x+32] is cleared. Error[8x+32] is cleared with "EN" fall edge or setting Memory address for ch#x DAC properly.
ERROR[31:24]	SPI transfer error (CRC un-match) has occurred during Write to memory for ch#x (x=0~7) 3LP data. If Error has occurred in ch(x), Register bit ERROR[8x+24] is set to "1" and "FAULT" pin becomes to "0" until ERROR[8x+24] is cleared. Error[8x+24] is cleared when the DATA for ch#x 3LP is transferred to memory normally.
ERROR[23:16]	SPI transfer error (CRC un-match) has occurred during Write to memory for ch#x (x=0~7) DAC data. If Error has occurred in ch(x), Register bit ERROR[8x+16] is set to "1" and "FAULT" pin becomes to "0" until ERROR[8x+16] is cleared. Error[8x+16] is cleared when the DATA for ch#x DAC is transferred to memory normally.
ERROR[15:8]	SPI transfer error (CRC un-match) has occurred during Write to Register on ch#x (x=0~7). If Error has occurred in ch(x), Register bit ERROR[8x+8] is set to "1" and "FAULT" pin becomes to "0" until ERROR[8x+8] is cleared. Error[8x+8] is cleared with "EN" fall edge or re-transferring the data to ch#x Register normally.

■ CRC & Error Register function (2)

Register parameter	Function
ERROR[7]	SPI transfer error (CRC un-match) has occurred during Write to Register#0~#11. If Error has occurred, Register bit ERROR[7] is set to "1" and "FAULT" pin becomes to "0" until ERROR[7] is cleared. Error[7] is cleared with "EN" fall edge or re-transferring the data to Register#0~#6 normally.
ERROR[6]	TRIG "hi" has occurred during SPI operation. If Error has occurred, Register bit ERROR[6] is set to "1" until it is cleared. Error[6] is cleared with "EN" fall edge.
ERROR[5]	Access to ch#x (x=0~7) 3LP memory has occurred during ch#x (x=0~7) 3LP Tx data is output. If Error has occurred, Register bit ERROR[5] is set to "1" until cleared. Error[5] is cleared with "EN" fall edge.
ERROR[4]	Access to ch#x (x=0~7) DAC memory has occurred during ch#x (x=0~7) DAC Tx operation. If Error has occurred, Register bit ERROR[4] is set to "1" until cleared. Error[4] is cleared with "EN" fall edge.
ERROR[3]	Ch#x (x=4~7) 3LP Tx data is output during "1" state of DRVSELB or transition period (640 clock cycle) from rise/fall edge. If Error has occurred, Register bit ERROR[3] is set to "1" and "FAULT" pin becomes to "0" until ERROR[3] is cleared. Error[3] is cleared with "EN" fall edge.
ERROR[2]	Ch#x (x=0~3) 3LP Tx data is output during "1" state of DRVSELA or transition period (640 clock cycle) from rise/fall edge. If Error has occurred, Register bit ERROR[2] is set to "1" and "FAULT" pin becomes to "0" until ERROR[2] is cleared. Error[2] is cleared with "EN" fall edge.
ERROR[1]	Ch#x (x=4~7) DAC Tx data is output during "0" state of DRVSELB or transition period (640 clock cycle) from rise/fall edge. If Error has occurred, Register bit ERROR[1] is set to "1" and "FAULT" pin becomes to "0" until ERROR[1] is cleared. Error[1] is cleared with "EN" fall edge.
ERROR[0]	Ch#x (x=0~3) DAC Tx data is output during "0" state of DRVSELA or transition period (640 clock cycle) from rise/fall edge. If Error has occurred, Register bit ERROR[0] is set to "1" and "FAULT" pin becomes to "0" until ERROR[0] is cleared. Error[0] is cleared with "EN" fall edge.

■ CRC & Error Register MAP

Function	REG.#	D7 (MSB)	D6	D5	D4	D3	D2	D1	D0 (LSB)	Default	W/R
CRC Code	C0				CRC[7:0]					00000000	W/R
	C1				CAL_CRC[7:0]					00000000	R
Error Code	E0	ERROR[47]	ERROR[46]	ERROR[45]	ERROR[44]	ERROR[43]	ERROR[42]	ERROR[41]	ERROR[40]	00000000	R
	E1	ERROR[39]	ERROR[38]	ERROR[37]	ERROR[36]	ERROR[35]	ERROR[34]	ERROR[33]	ERROR[32]	00000000	R
	E2	ERROR[31]	ERROR[30]	ERROR[29]	ERROR[28]	ERROR[27]	ERROR[26]	ERROR[25]	ERROR[24]	00000000	R
	E3	ERROR[23]	ERROR[22]	ERROR[21]	ERROR[20]	ERROR[19]	ERROR[18]	ERROR[17]	ERROR[16]	00000000	R
	E4	ERROR[15]	ERROR[14]	ERROR[13]	ERROR[12]	ERROR[11]	ERROR[10]	ERROR[9]	ERROR[8]	00000000	R

**OCTAL DAC WITH DIFFERENTIAL OUTPUTS AND 2-BIT PER CHANNEL CMOS OUTPUT
PATTERN GENERATORS FOR ULTRASOUND TRANSMITTER**
S-US55D2

Rev.1.2_00

■ Truth Table

IC status	EN	CS			TRIG	Internal Tx-PT(x)	Driver Select	Control Register				Ch(x) DAC MEM. Readout code	Ch(x) TLP MEM. Readout code	Control Register		Ch(x) DAC digital input CHxDAC[11:0]	DAC Ic Bias On/Off	DRVSELy (y=A for ch0~3, y=B for ch4~7), Ch(x) (x=0~7) TLP DATA & DAC current					
		to Ch(x) DAC MEM.	to Ch(x) TLP MEM.	to control REG.				DACTX CHx	TLP TX CHx	PWR SAVE	RXCHx			CHxDATA (dec)	CHxCODE[1:0]	INVx	GAINx[5:0]	CHxDAC (*1) (dec)	BIASONx	DRVSELy	PINx	NINx	CHx DAC IOP-ION
mode		0	0	0	0	none	*	0	0	0	0	none	none	none	*	*	none	1	0	0	0	0(bias-on)	
Rx	0	0	0	0	0	none	*	0	0	0	1	none	none	none	*	*	none	1	0	1	1	0(bias-on)	
	0	0	0	0	0	none	*	0	0	1	0	none	none	none	*	*	none	0	0	0	0	0(bias-off)	
	0	0	0	0	0	none	*	0	0	1	1	none	none	none	*	*	none	0	0	1	1	0(bias-off)	
	0	0	0	0	0	none	*	1	*	*	0	none	none	none	*	*	none	1	1	0	0	0(bias-on)	
	0	0	0	0	0	none	*	1	*	*	1	none	none	none	*	*	none	1	1	1	1	0(bias-on)	
	0	0	0	0	0	none	*	1	*	*	1	none	none	none	*	*	none	1	0	0	0	0(bias-on)	
TLP Tx	0	0	0	0	Gen.	0(TLP)	*	1	*	*	none	0	0	*	*	none	1	0	0	0	0	0(bias-on)	
	0	0	0	0	Gen.	0(TLP)	*	1	*	*	none	0	1	0	*	none	1	0	1	0	0	0(bias-on)	
	0	0	0	0	Gen.	0(TLP)	*	1	*	*	none	0	1	1	*	none	1	0	0	0	1	0(bias-on)	
	0	0	0	0	Gen.	0(TLP)	*	1	*	*	none	1	0	0	*	none	1	0	0	1	0	0(bias-on)	
	0	0	0	0	Gen.	0(TLP)	*	1	*	*	none	1	0	1	*	none	1	0	0	1	0	0(bias-on)	
	0	0	0	0	Gen.	0(TLP)	*	1	*	*	none	1	1	*	*	none	1	0	0(N/A)	0(N/A)	0	0(bias-on)	
DAC Tx	0	0	0	0	Gen.	1(DAC)	1	*	*	*	CHxDATA	none	none	0	GAINx	(GAINx+1)/64*CHxDATA	1	1	0	0	0	2*Ic*CHxDAC	
	0	0	0	0	Gen.	1(DAC)	1	*	*	*	CHxDATA	none	none	1	GAINx	-1*(GAINx+1)/64*CHxDATA	1	1	1	0	0	2*Ic*CHxDAC	
TRIG_Reset	0	0	0	1	none	*	0	0	0	0	none	none	none	*	*	none	1	0	0	0	0	0(bias-on)	
	0	0	0	1	none	*	0	0	0	1	none	none	none	*	*	none	1	0	1	1	0	0(bias-on)	
	0	0	0	1	none	*	0	0	1	0	none	none	none	*	*	none	0	0	0	0	0	0(bias-off)	
	0	0	0	1	none	*	0	0	1	1	none	none	none	*	*	none	0	0	0	1	1	0(bias-off)	
	0	0	0	1	none	*	1	*	*	0	none	none	none	*	*	none	1	1	0	0	0	0(bias-on)	
	0	0	0	1	none	*	1	*	*	1	none	none	none	*	*	none	1	1	1	1	0	0(bias-on)	
REG Access during Rx	0	-	-	1	0	none	*	0	0	0	0	none	none	none	*	*	none	1	0	0	0	0	0(bias-on)
	0	-	-	1	0	none	*	0	0	0	1	none	none	none	*	*	none	1	0	1	1	0	0(bias-on)
	0	-	-	1	0	none	*	0	0	1	0	none	none	none	*	*	none	0	0	0	0	0	0(bias-off)
	0	-	-	1	0	none	*	0	0	1	1	none	none	none	*	*	none	0	0	1	1	0	0(bias-off)
	0	-	-	1	0	none	*	1	*	*	0	none	none	none	*	*	none	1	1	0	0	0	0(bias-on)
	0	-	-	1	0	none	*	1	*	*	1	none	none	none	*	*	none	1	1	1	1	0	0(bias-on)
REG Access during TLP Tx	0	-	-	1	0	Gen.	0(TLP)	*	1	*	*	none	0	0	*	*	none	1	0	0	0	0	0(bias-on)
	0	-	-	1	0	Gen.	0(TLP)	*	1	*	*	none	0	1	0	*	none	1	0	1	0	0	0(bias-on)
	0	-	-	1	0	Gen.	0(TLP)	*	1	*	*	none	0	1	1	*	none	1	0	0	0	1	0(bias-on)
	0	-	-	1	0	Gen.	0(TLP)	*	1	*	*	none	1	0	0	*	none	1	0	0	0	1	0(bias-on)
	0	-	-	1	0	Gen.	0(TLP)	*	1	*	*	none	1	1	*	*	none	1	0	0(N/A)	0(N/A)	0	0(bias-on)
	0	-	-	1	0	Gen.	1(DAC)	1	*	*	*	CHxDATA	none	none	0	GAINx	(GAINx+1)/64*CHxDATA	1	1	0	0	0	2*Ic*CHxDAC
REG Access during DAC TX (*2)	0	-	-	1	0	Gen.	1(DAC)	1	*	*	*	CHxDATA	none	none	1	GAINx	-1*(GAINx+1)/64*CHxDATA	1	1	1	0	0	2*Ic*CHxDAC

*1: The decimal point is suppressed.

*2: If ICSELx[2:0] and GAINADJx[7:0] are changed during ch(x) DAC operating, ch(x) DAC output current will be varied.

■ Truth Table (continuation)

IC status	EN	CS			TRIG	Internal Tx-PT(x)	Driver Select	Control Register				Ch(x) DAC MEM. Readout code	Ch(x) TLP MEM. Readout code	Control Register		Ch(x) DAC digital input CHxDAC[11:0]	DAC Ic Bias On/Off	DRVSELy (y=A for ch0~3, y=B for ch4~7), Ch(x) (x=0~7) TLP DATA & DAC current					
		to Ch(x) DAC MEM.	to Ch(x) TLP MEM.	to control REG.				DACTX CHx	TLP TX CHx	PWR SAVE	RXCHx	CHxDATA (dec)	CHxCODE[1:0]	INVx	GAINx[5:0]	CHxDAC (*1) (dec)	BIASONx	DRVSELy	PINx	NINx	CHx DAC IOP-ION		
Ch(x) TLP MEM Access during Rx	0	-	1	-	0	none	*	0	0	0	0	none	none	none	*	*	none	1	0	0	0	0(bias-on)	
	0	-	1	-	0	none	*	0	0	0	1	none	none	none	*	*	none	1	0	1	1	0(bias-on)	
	0	-	1	-	0	none	*	0	0	1	0	none	none	none	*	*	none	0	0	0	0	0(bias-off)	
	0	-	1	-	0	none	*	0	0	1	1	none	none	none	*	*	none	0	0	1	1	0(bias-off)	
	0	-	1	-	0	none	*	1	*	*	0	none	none	none	*	*	none	1	1	0	0	0(bias-on)	
	0	-	1	-	0	none	*	1	*	*	1	none	none	none	*	*	none	1	1	1	1	0(bias-on)	
	Ch(x) TLP MEM. Access during TLP Tx	0	-	1	-	0	Gen.	0(TLP)	*	1	*	*	none	*	*	*	*	none	1	Error condition (ERROR[5]=1) N/A			
Ch(x) TLP MEM. Access during DAC Tx	0	-	1	-	0	Gen.	1(DAC)	1	*	*	*	*	CHxDATA	none	none	0	GAINx	(GAINx+1)/64*CHxDATA	1	1	0	0	2*Ic*CHxDAC
	0	-	1	-	0	Gen.	1(DAC)	1	*	*	*	*	CHxDATA	none	none	1	GAINx	-1*(GAINx+1)/64*CHxDATA	1	1	0	0	2*Ic*CHxDAC
Ch(x) DAC MEM. Access during Rx	0	1	-	-	0	none	*	0	0	0	0	none	none	none	*	*	none	1	0	0	0	0(bias-on)	
	0	1	-	-	0	none	*	0	0	0	1	none	none	none	*	*	none	1	0	1	1	0(bias-on)	
	0	1	-	-	0	none	*	0	0	1	0	none	none	none	*	*	none	0	0	0	0	0(bias-off)	
	0	1	-	-	0	none	*	0	0	1	1	none	none	none	*	*	none	0	0	1	1	0(bias-off)	
	0	1	-	-	0	none	*	1	*	*	0	none	none	none	*	*	none	1	1	0	0	0(bias-on)	
	0	1	-	-	0	none	*	1	*	*	1	none	none	none	*	*	none	1	1	1	1	0(bias-on)	
	Ch(x) DAC MEM. Access during TLP Tx	0	1	-	-	0	Gen.	0(TLP)	*	1	*	*	none	0	0	*	*	none	1	0	0	0	0(bias-on)
Ch(x) DAC MEM. Access during DAC Tx	0	1	-	-	0	Gen.	0(TLP)	*	1	*	*	none	0	1	0	*	none	1	0	1	0	0(bias-on)	
	0	1	-	-	0	Gen.	0(TLP)	*	1	*	*	none	0	1	1	*	none	1	0	0	1	0(bias-on)	
	0	1	-	-	0	Gen.	0(TLP)	*	1	*	*	none	1	0	0	*	none	1	0	0	1	0(bias-on)	
	0	1	-	-	0	Gen.	0(TLP)	*	1	*	*	none	1	0	1	*	none	1	0	1	0	0(bias-on)	
	0	1	-	-	0	Gen.	0(TLP)	*	1	*	*	none	1	0	1	*	none	1	0	1	0	0(bias-on)	
	0	1	-	-	0	Gen.	0(TLP)	*	1	*	*	none	1	1	*	*	none	1	0	0(N/A)	0(N/A)	0(bias-on)	
Ch(x) DAC MEM. Access during DAC Tx	0	1	-	-	0	Gen.	1(DAC)	1	*	*	*	none	*	*	*	*	none	1	Error condition (ERROR[4]=1) N/A				
TRIG rise during CS=Hi	0	1			1	*	*	*	*	*	*	none	*	*	*	*	none	*	Error condition (ERROR[6]=1) N/A				
IC disabled	1	0			*	none	*	*	*	*	*	none	*	*	*	*	none	0	0	0	0	0(bias-off)	
SPI access during IC disabled	1	-	-	1	*	none	*	*	*	*	*	none	*	*	*	*	none	0	0	0	0	0(bias-off)	
	1	-	1	-	*	none	*	*	*	*	*	none	*	*	*	*	none	0	0	0	0	0(bias-off)	
	1	1	-	-	*	none	*	*	*	*	*	none	*	*	*	*	none	0	0	0	0	0(bias-off)	

*1: The decimal point is suppressed.

*2: If ICSELx[2:0] and GAINADJx[7:0] are changed during ch(x) DAC operating, ch(x) DAC output current will be varied.

**OCTAL DAC WITH DIFFERENTIAL OUTPUTS AND 2-BIT PER CHANNEL CMOS OUTPUT
PATTERN GENERATORS FOR ULTRASOUND TRANSMITTER**
S-US55D2

Rev.1.2_00

■ PIN Descriptions

Pin#	Pin Name	Function	Pin#	Pin Name	Function
1	SPI_OFF	Control of SPI On/Off (H:Power-off,L:Power-on(50kΩ pull-down))	35	DAC _{OUTP6}	CH6 DAC differential outputs
2	SDOUT	SPI serial output data (tri-state output)	36	DAC _{OUTN6}	
3	VLL	Positive low voltage power supply for Logic (+1.8V)	37	DAC _{OUTP5}	CH5 DAC differential outputs
4	CSP	Positive LVDS chip select (CS) input	38	DAC _{OUTN5}	
5	CSN	Negative LVDS chip select (CS) input	39	DAC _{OUTP4}	CH4 DAC differential outputs
6	SDATAP	Positive LVDS Serial Data input	40	DAC _{OUTN4}	
7	SDATAN	Negative LVDS Serial Data input	41	AGND	Reserved for Testing (Connected to GND)
8	SCLKP	Positive LVDS serial clock input (up to 100MHz)	42	RBGR	Output for Constant Reference Current (Connect 24kΩ to GND)
9	SCLKN	Negative LVDS serial clock input (up to 100MHz)	43	FAULT	Fault output flag, Open N-MOS Drain (H:Normal, L:Fault)
10	DGND	GND for Digital Power Supplies	44	AVSS	Negative Analog Power Supply for DAC (-2~0V)
11	CLKP	Positive LVDS clock input (up to 200MHz)	45	VCOMREF	Output common voltage reference
12	CLKN	Negative LVDS clock Input (up to 200MHz)	46	DAC _{OUTN3}	CH3 DAC differential outputs
13	DVDD	Positive Digital Power Supply for LVDS Receiver (+3.3V)	47	DAC _{OUTP3}	
14	TRIG	Trigger signal for operation (CMOS)	48	DAC _{OUTN2}	CH2 DAC differential outputs
15	VLL	Positive low voltage power supply for Logic (+1.8V)	49	DAC _{OUTP2}	
16	EN	IC Disable/Enable control (H: Disable (50kΩ pull-up), L:Enable)	50	DAC _{OUTN1}	CH1 DAC differential outputs
17	SPI_IF	I/F selection for SPI (H:Single CMOS, L:LVDS(default))	51	DAC _{OUTP1}	
18	VLLIO	Positive low voltage power supply for Logic I/F (+1.8 ~ 3.3V)	52	DAC _{OUTN0}	CH0 DAC differential outputs
19	P _{IN} 7	2bit Tx data for ch7 3LP	53	DAC _{OUTP0}	
20	N _{IN} 7		54	AGND	GND for Analog Power Supplies
21	P _{IN} 6	2bit Tx data for ch6 3LP	55	AVDD	Positive Analog Power Supply for DAC (+3.3V)
22	N _{IN} 6		56	DGND	GND for Digital Power Supplies
23	P _{IN} 5	2bit Tx data for ch5 3LP	57	TXONFLAG	Tx DATA output flag, Open N-MOS Drain (L:Outputting Tx DATA)
24	N _{IN} 5		58	DRVSELA	Driver select signal for ch0~3
25	P _{IN} 4	2bit Tx data for ch4 3LP	59	EXT_SIGA	External driver select input for ch0~3
26	N _{IN} 4		60	N _{IN} 3	2bit Tx data for ch3 TLP
27	EXT_SIGB	External driver select input for ch4~7	61	P _{IN} 3	
28	DRVSELB	Driver select signal for ch4~7	62	N _{IN} 2	2bit Tx data for ch2 TLP
29	DGND	Reserved for Testing (Connected to GND)	63	P _{IN} 2	
30	DGND	GND for Digital Power Supplies	64	N _{IN} 1	2bit Tx data for ch1 TLP
31	AVDD	Positive Analog Power Supply for DAC (+3.3V)	65	P _{IN} 1	
32	AGND	GND for Analog Power Supplies	66	N _{IN} 0	2bit Tx data for ch0 TLP
33	DAC _{OUTP7}	CH7 DAC differential outputs	67	P _{IN} 0	
34	DAC _{OUTN7}		68	VLLIO	Positive low voltage power supply for Logic I/F (+1.8 ~ 3.3V)

■ PIN Configuration

	VLLIO	PIN0	NIN0	PIN1	NIN1	PIN2	NIN2	PIN3	NIN3	EXT_SIGA	DRVSEL A	TXONFLAG	DGND	AVDD	AGND	DACOUTP0	DACOUTN0	
●	68	67	66	65	64	63	62	61	60	59	58	57	56	55	54	53	52	
SPI_OFF	1															51	DACOUTP1	
SDOUT	2															50	DACOUTN1	
VLL	3															49	DACOUTP2	
CSP	4															48	DACOUTN2	
CSN	5															47	DACOUTP3	
SDATAP	6															46	DACOUTN3	
SDATAN	7															45	VCOMREF	
SCLKP	8															44	AVSS	
SCLKN	9															43	FAULT	
DGND	10															42	RBGR	
CLKP	11															41	AGND	
CLKN	12															40	DACOUTN4	
DVDD	13															39	DACOUTP4	
TRIG	14															38	DACOUTN5	
VLL	15															37	DACOUTP5	
EN	16															36	DACOUTN6	
SPI_IF	17															35	DACOUTP6	
	18	19	20	21	22	23	24	25	26	27	28	29	30	31	32	33	34	
	VLLIO	PIN7	NIN7	PIN6	NIN6	PIN5	NIN5	PIN4	NIN4	EXT_SIGB	DRVSEL B	DGND	DGND	AVDD	AGND	DACOUTP7	DACOUTN7	

OCTAL DAC WITH DIFFERENTIAL OUTPUTS AND 2-BIT PER CHANNEL CMOS OUTPUT PATTERN GENERATORS FOR ULTRASOUND TRANSMITTER

Rev.1.2_00

S-US55D2

■ Package

Package Name	Dimension	Tray	Marking	Land	Packing
QFN-68(1010)B	QN068-B-P-SD	QN068-B-T-SD	QN068-B-M-SD	QN068-B-L-SD	QN068-B-K-SD

■ Storage, Mounting

1. Storage conditions

1. 1 The storage location should be kept at 5 to 35°C and 40 to 70% relative humidity. Keeping in a dry box is recommended. Moisture-proof property is assured for 12 months from delivery date for sealed moisture-proof packing, while it is guaranteed for 7 days from unpacked date under the condition above.
1. 2 When the storage conditions do not conform to those above or other conditions occur indicating moisture exposure, the ICs should be dried to avoid package cracks. A baking process at 125°C lasting for 24 hours results in sufficient dehumidification. The baking is not allowed more than twice, and the ICs should be mounted within 7 days after initial baking or within 10 days of total exposure after the second dehumidification.

2. Reflow soldering

The temperature rise may be different in the resin and a terminal part due to the reflow soldering.

It is necessary to check the package surface temperature (resin) before setting the temperature profile.

Figure 1 shows the resistance to soldering heat condition for package (Reflow method).

Confirm the heat resistance of the package shown below. (Based on JEDEC J-STD-020).

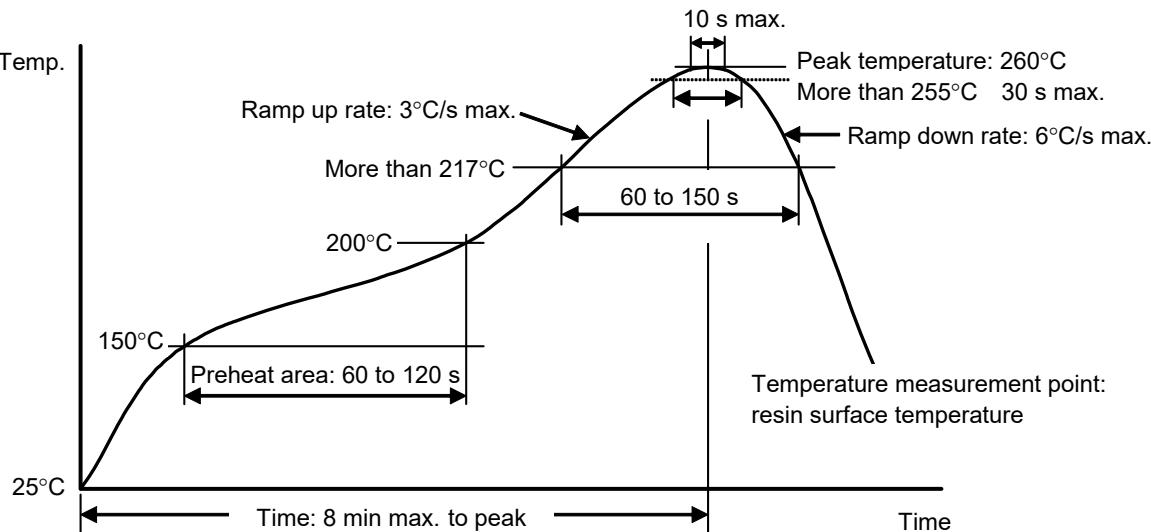


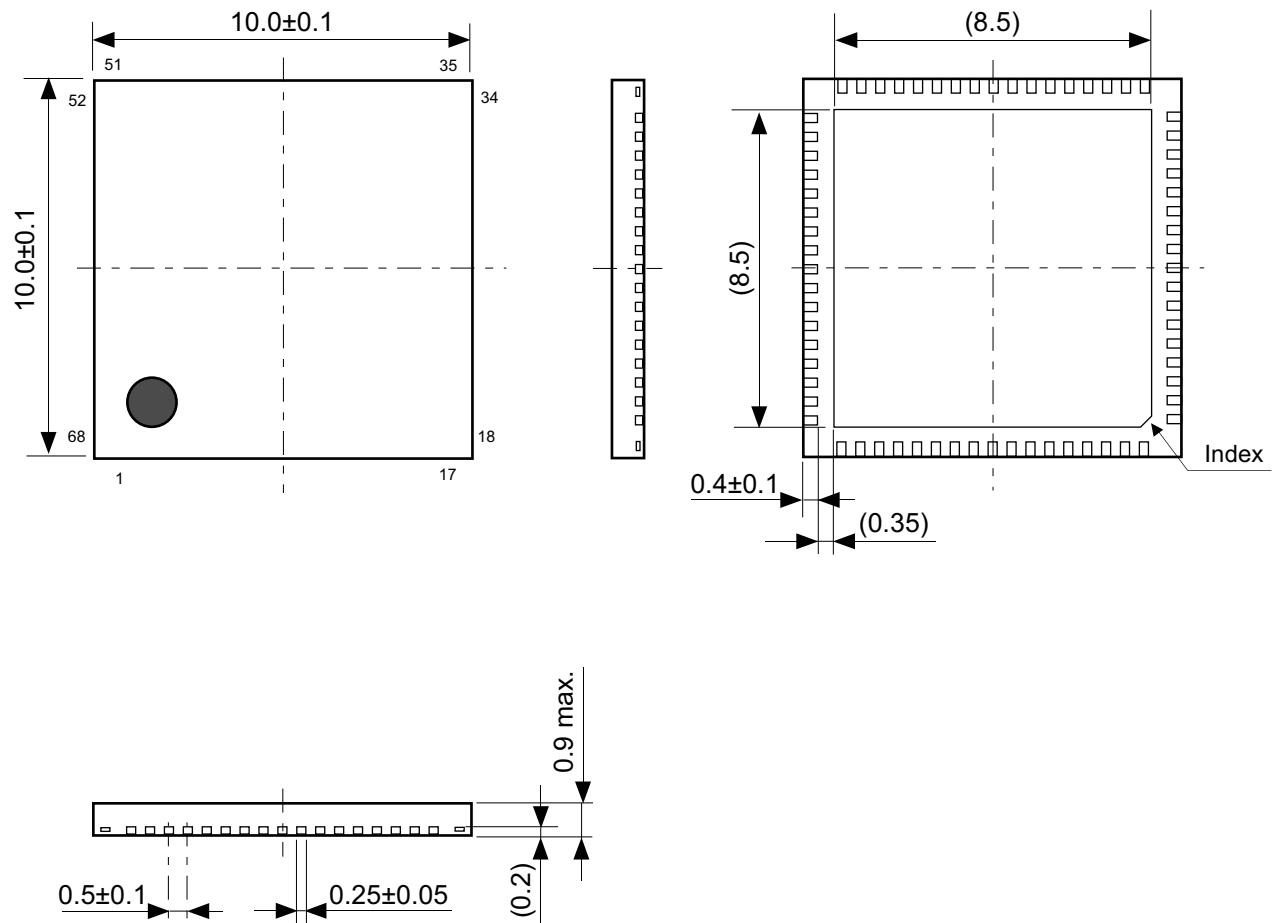
Figure 1 Resistance to Soldering Heat Condition for Package (Reflow Method)

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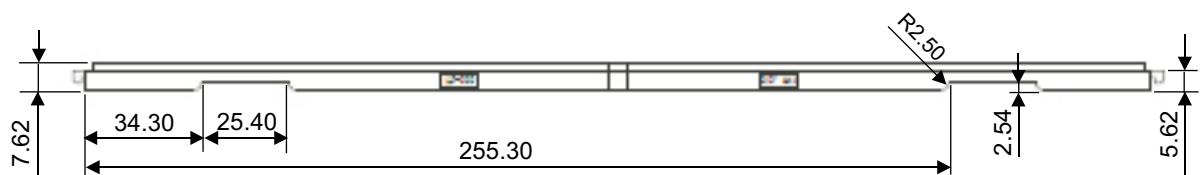
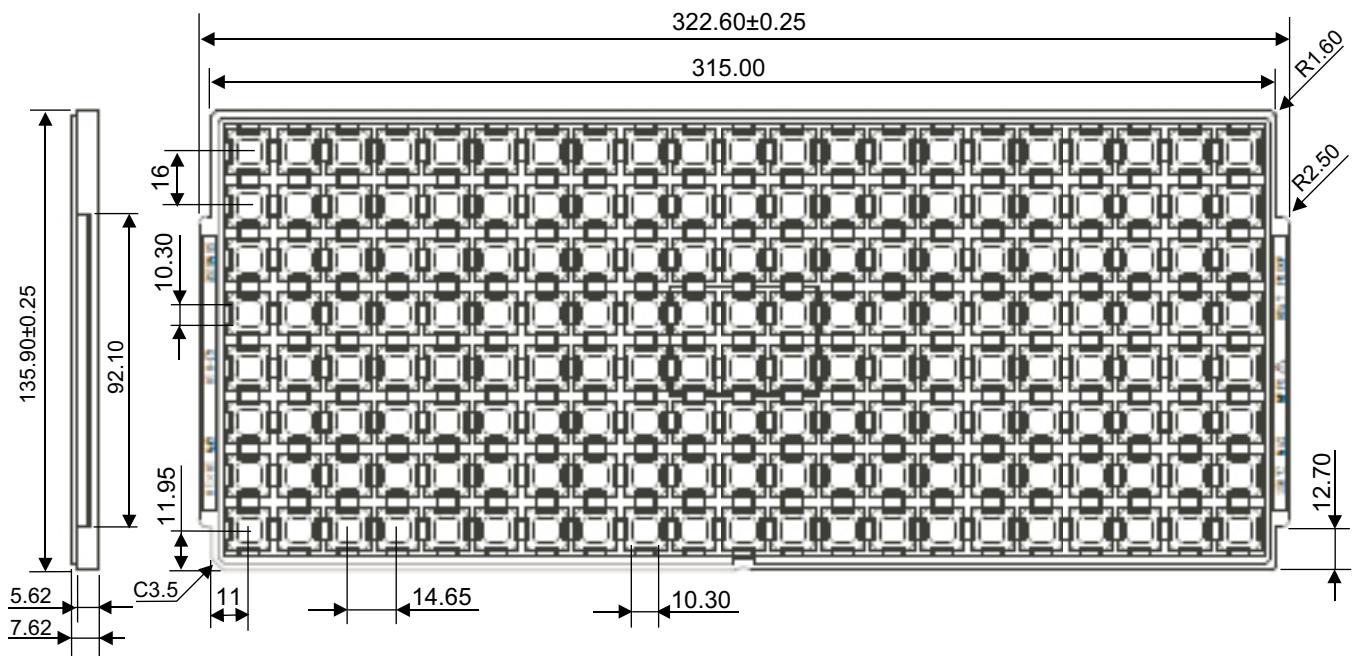
■ Cautions

1. Customers are advised to follow the cautions below to protect products from damage caused by electrical static discharge (ESD).
 1. 1 Material of container or any device to carry products should be free from ESD, which may be caused by vibration while transportation. It is recommended that electric-conductive container or aluminum sheet be used as an effective countermeasure.
 1. 2 Those that touch products, such as work platform, machine, or measurement/test equipment, should be grounded.
 1. 3 Those who deal with products should be grounded through a large series impedance around $100k\Omega$ to $1M\Omega$.
 1. 4 Prevent friction with other materials made with high polymer.
 1. 5 Prevent vibration or friction when carrying the printed circuit board (PCB) where products are mounted. To short circuit terminals is a recommended countermeasure to keep the same electric potential on the PCB.
 1. 6 Avoid dealing with or storing products in an extremely arid environment.
2. "Absolute maximum ratings" should never be exceeded during use regardless of any change in external conditions. Otherwise, products may be damaged or destroyed. In no event shall ABLIC Inc. be liable for any failure in products or any secondary damage resulting from use at a value exceeding the absolute maximum ratings.
3. Products may experience failures due to accident or unexpected surge voltages. Accordingly, adopt safe design features, such as redundancy or prevention of erroneous action, to avoid extensive damage in the event of a failure. (If a semiconductor device fails, there may be cases in which the semiconductor device, wiring or wiring pattern will emit smoke or cause a fire or in which the semiconductor device will burst.)
4. Products may experience failures or malfunction in poor surroundings, such as electrical leakage in products due to long-term use in high humidity, malfunctioning or permanent damage due to chemical reaction of products in corrosive environment or due to discharge by strongly charged object near products or due to excessive mechanical shock. To use products in radiation environment is not assumed. To use products near material easy to ignite may cause a fire due to its flammable package. Avoid using products in such environment or take appropriate countermeasures depending on the environment.
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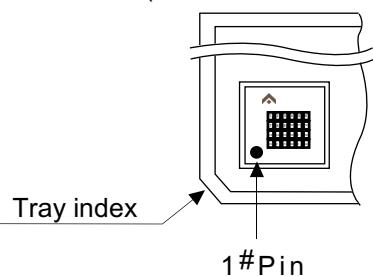


No. QN068-B-P-SD-2.0

TITLE	QFN68-B-PKG Dimensions
No.	QN068-B-P-SD-2.0
ANGLE	⊕ ↗
UNIT	mm
ABLIC Inc.	

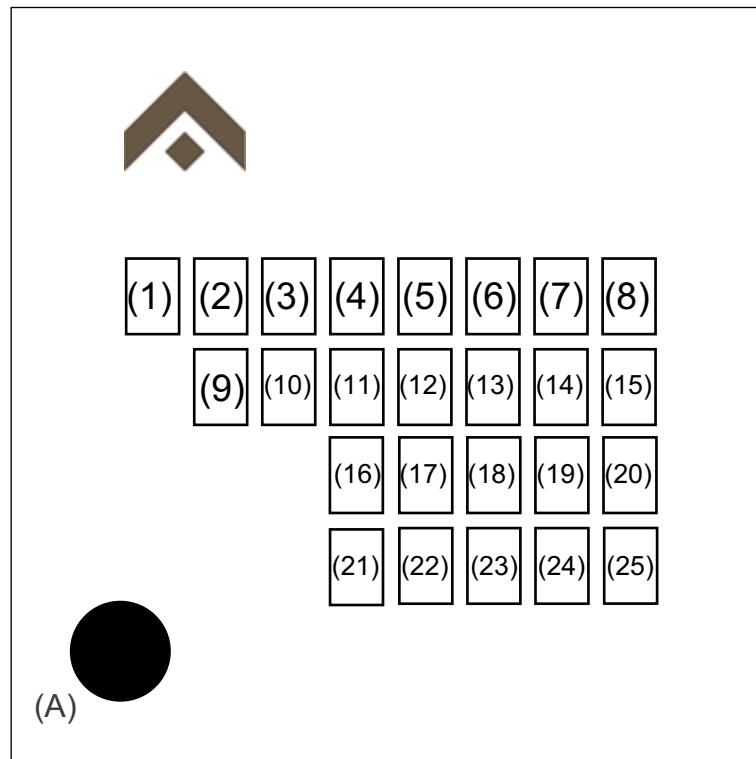


(Direction of IC in tray)



No. QN068-B-T-SD-1.0

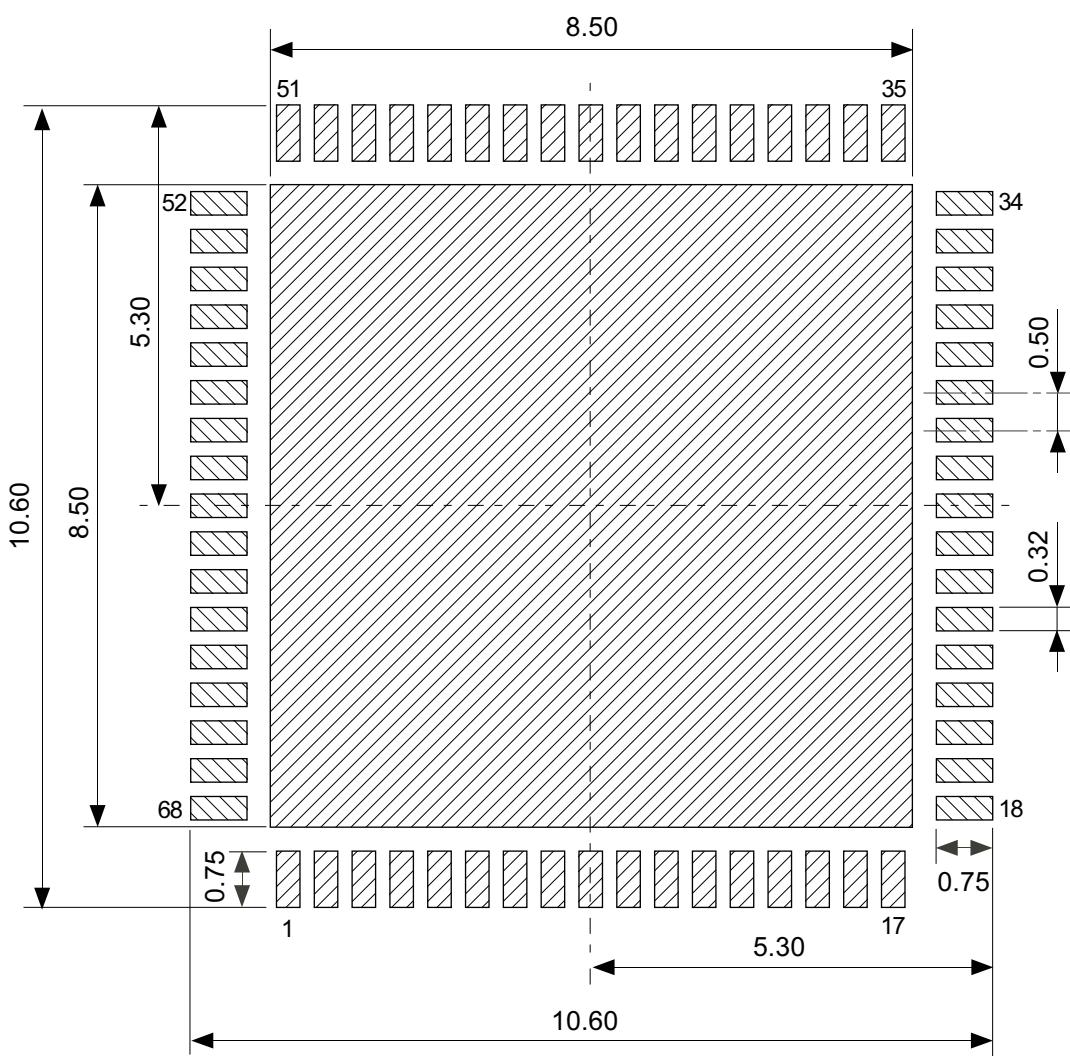
TITLE	QFN68-B-Tray		
No.	<u>QN068-B-T-SD-1.0</u>		
ANGLE		QTY.	168
UNIT	mm		
ABLIC Inc.			



- (1) to (10) : Product code
- (11), (12) : Quality control code
- (13) : Year of assembly
- (14) : Month of assembly
- (15) : Week of assembly
- (16) to (25) : Quality control code
- (A) : 1-pin mark

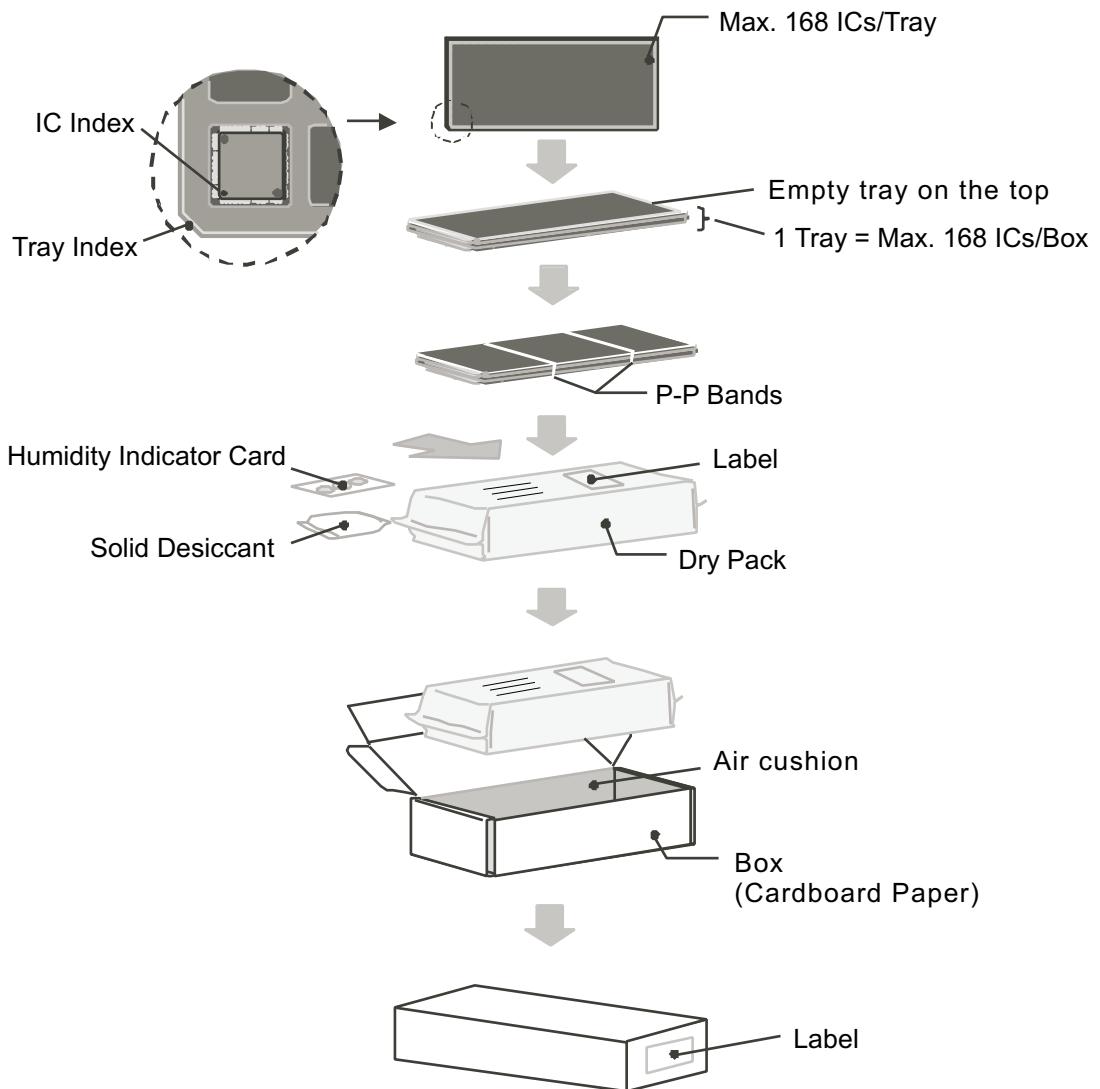
No. QN068-B-M-SD-2.0

TITLE	QFN68-B-Markings		
No.	QN068-B-M-SD-2.0		
ANGLE			
UNIT		TYPE	LASER
ABLIC Inc.			



No. QN068-B-L-SD-2.0

TITLE	QFN68-B -Land Recommendation
No.	QN068-B-L-SD-2.0
ANGLE	
UNIT	mm
ABLIC Inc.	



No. QN068-B-K-SD-2.0

TITLE	QFN68-B -Packing Procedure
No.	QN068-B-K-SD-2.0
ANGLE	
UNIT	
ABLIC Inc.	

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2.4-2019.07

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